

Lab 0 - Implementation

- It consists of MBIST, Synthesis, Scan (with out wrappers), ATPG, Simulations.

Step 1: MBIST Insertion

```
MemoryTemplate (SYNC_1R1W_16x8) { // {{{
    MemoryType      : SRAM; // PG mandatory
    CellName        : SYNC_1R1W_16x8;
    Algorithm       : SMarchCHKBvcd;
    BitGrouping     : 1;
    //ShadowWrite    : On;
    //ShadowWriteOK  : On;
    //ShadowRead     : On;
    //ReadOutOfRangeOK : On;
    TransparentMode : SyncMux;
    //DataOutStage   : None;
    OperationSet    : Sync;
    LogicalPorts    : 1R1W;
```

Sync Mux means adding a logic to bypass the memory

So memory has to be bypass during Scan, ATPG, EDT and tool will add a logic to bypass the memories

```
1 /**
2 /**
3 /**
4 /**
5 /**
6 /**
7
8
9 ### context "dft rtl" tell the tool to enter into RTL insertion mode, design_id tells to create a separate directory in t
  sdb for this particular below insertion steps. -design_id <your custom name for this insertion , for example first_insert
  ion>
10 set_context dft -rtl -design_id first_insertion
11
12 ## specify the output directory where you want to dump the outputs of mbist insertion
13 set_tsdb_output_directory ..//tsdb_outdir
14
15 ## provide the design files and library files
16 read_cell_library ../../library/adk.tcelllib
17
18 read_verilog ../../library/mems/SYNC_1R1W_16x8.v -exclude_from_file_dictionary -verbose
19
20 read_verilog ..//design/corea.v -verbose
21
22 ## Elaborate the design
23 set_current_design corea
24
25 # set the design level to either chip, physical_block or sub_block
26 set_design_level physical_block
27
28 ## declare the clocks and constraints
29 add_clocks 0 clka -period 10ns
30 add_clocks 0 clkb -period 13.2ns
31 ##add_clocks 0 clkc -period 14ns
```

```
32
33 set_dft_specification_requirements -memory_test on
34
35 /**/
```

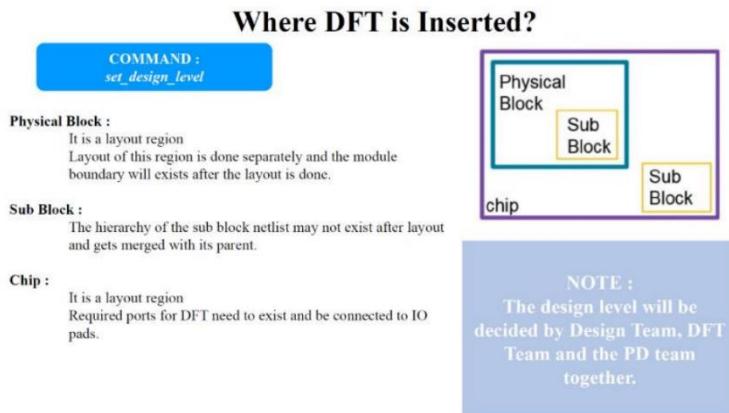
Line 10: Inside the tsdb output directory a sub-directory with this design id will be created and all the outputs with this particular run it will be stored into that particular directory

Line13: By default it will be created in current directory, so our current directory is MBIST Insertion. But for complete lab0 to have common tsdb output directory

Line 16,18,20: Reading the library files, the memory file and the corea we are reading.

Line 23: Setting the current design of corea and it will do elaboration, it will check whether all the module definition is available or not and whether module instantiation is correct or not.

Line 26: set_design_level physical_block



Line 33: -memory_test on means we are doing MBIST Insertion and if we -logic_test on means we are doing EDT and OCC Insertion.

Whatever the test hardware has inserted into MBIST insertion run that will be included into the dft specification

Specifying DFT Requirement

- Specifies the requirements to be checked during `check_design_rules`.

Command : `set_dft_specification_requirements -memory_test on`

- "-memory_test on" option is needed when implementing memory test.
- When memory_test on, memory_bist, memory_bisr_chains, and memory_bisr_controller default to auto; otherwise they are default to off.
- When memory_bist option is set to auto, if the current design contains memories, the MBIST pre-DFT DRC rules will be checked during `check_design_rules` command. The required specifications will also be included to the DFT specification when the command `create_dft_specification` is executed.

```
35 #//
36 #//
37 #//
38 #//
39 #//
40 #//
41
42 ## DFT Signals
43 add_dft_signal ltest_en int_mode ext_mode tck_occ_en int_ltest_en ext_ltest_en // should be enabled if we go for wrapper
s in scan
44 add_dft_signal scan_en -source_node scan_en
45 add_dft_signal shift_capture_clock -source_node test_clock
46
47
48
49 check_design_rules
```

Line 44: Only static signals can be controlled by TDR

Line 45: Scan Enable will be controlled by the top level ports scan enable.
Source node that is scan_en will be controlled by top level port i.e. scan_en

Line 46: Shift capture clock it will be controlled by the top level port test clock

So we will run till line 49 in tessent tool

```
/home/vinayakp/aug23/level3/Lab0/mbist_insertion>>tessent -shell -dofile corea_mbist.tcl
// Warning: Tessent user documentation not found
// Tessent Shell 2021.1   Fri Feb 26 20:45:56 GMT 2021
//           Copyright 2011-2021 Mentor Graphics Corporation
//
//           All Rights Reserved.
//
// THIS WORK CONTAINS TRADE SECRET AND PROPRIETARY INFORMATION WHICH
// IS THE PROPERTY OF MENTOR GRAPHICS CORPORATION OR ITS LICENSORS AND IS
// SUBJECT TO LICENSE TERMS.
//
// Mentor Graphics software executing under x86-64 Linux on Fri Dec 22 20:36:20 IST 2023.
// 64 bit version
// Host: vlsiguru (64168 MB RAM, 32191 MB Swap)
//
// mtnslogicbist_c license will expire in 5 days...
// command: #/
// command: #/      --- | | \ / --- | --- /|
// command: #/      |_ _| - -| / \ \ | --- | ===| ===| /|
// command: #/      | | | /-----\ | | --- | ===| ===| /|
// command: #/      | | | / \ \ \ | | --- | ===| ===| /|
// command: ### context "dft rtl" tell the tool to enter into RTL insertion mode, design_id tells to create a :
// erate directory in tsdb for this particular below insertion steps. -design_id <your custom name for this inser-
// tion , for example first_insertion>
// command: set_context dft -rtl -design_id first_insertion

// mtijtag_c license will expire in 5 days...
// command: ## specify the output directory where you want to dump the outputs of mbist insertion
// command: set_tsdb_output_directory ./tsdb outdir
// command: ## provide the design files and library files
// command: read_cell_library ../../library/adk.tcelllib

// Reading DFT Library file ../../library/adk.tcelllib
// Finished reading file ../../library/adk.tcelllib
// command: read_verilog ../../library/mems/SYNC_IIR1W_16x8.v -exclude_from_file_dictionary -verbose
// Reading Verilog file ../../library/mems/SYNC_IIR1W_16x8.v
// Finished reading file ../../library/mems/SYNC_IIR1W_16x8.v
// command: read_verilog ../design/corea.v -verbose
// Reading Verilog file ../design/corea.v
// Finished reading file ../design/corea.v
// command: ## Elaborate the design
// command: set_current_design corea
// command: # set the design level to either chip, physical_block or sub_block
// command: set_design_level physical_block
// command: ## declare the clocks and constraints
// command: add_clocks 0 clka -period 10ns
// command: add_clocks 0 clkb -period 13.2ns
// command: ##add_clocks 0 clkc -period 14ns
// command: set_dft_specification_requirements -memory_test on

// mttsmemorybist_c license will expire in 5 days...
// command: #/
// command: #/      --- | | \ / --- | --- /|
// command: #/      |_ _| - -| / \ \ | --- | ===| ===| /|
// command: #/      | | | /-----\ | | --- | ===| ===| /|
// command: #/      | | | / \ \ \ | | --- | ===| ===| /|
// command: ## DFT Signals
// command: #add_dft_signal ltest_en int_mode ext_mode tck_occ_en int_ltest_en ext_ltest_en // should be enable
// d if we go for wrappers in scan
// command: add_dft_signals ltest_en
// command: add_dft_signals scan_en -source_node scan_en
// command: add_dft_signals shift_capture_clock -source_node test_clock
// command: check design rules

// Begin RTL synthesis.
// -----
// Synthesized modules=1, Time=1.94 sec.
// Note: There was 1 module selectively synthesized. There were also 5 sub-modules created by synthesis.
//       Use 'get_module -filter is_synthesized' to see them.
//       You can also use 'set_quick_synthesis_options -verbose on' to have the synthesis step report the
//       synthesized module name in the transcript as it is being synthesized.
// -----
// Warning: Rule FN4 violation occurs 2 times
// Flattening process completed, cell instances=844, gates=4383, PIs=70, P0s=64, CPU time=0.01 sec.
// -----
// Begin circuit learning analyses.
// -----
// Learning completed, CPU time=0.01 sec.
// command: stop
// Error: Command 'stop' is unknown
// 'DOFile_corea_mbist.tcl' aborted at line 50
```

```
~'
28 ## declare the clocks and constraints
29 add_clocks 0 clka -period 10ns
30 #add_clocks 0 clkcb -period 13.2ns
31 ##add_clocks 0 clkcb -period 14ns
32
```

If u have missed the clock declaration

```
// -----
// Learning completed, CPU time=0.01 sec.
// Error: The memory clock pin 'ram2/CLKR' (89.29) is sourced by port 'clkcb' (2.0)
//       but its period was not defined using the 'add_clocks -period' command. (DFT_C1-1)
// Error: There was 1 DFT_C1 violation (Memory clock not properly sourced by a declared clock).
// Error: Rules checking unsuccessful, cannot exit SETUP mode.
// 'DOFile corea_mbist.tcl' aborted at line 49
```

```

50 /**
51 /**
52 /**
53 /**
54 /**
55 /**
56
57
58
59 create_dft_specification
60 report_config_data
61 ### This command will start inserting the mbist/sib network logic ( hardware implementation)
62 process_dft_specification
63
64 ## Till above command, tool will be in insertion state, giving below command will make the tool to shift to setup state
65 extract_icl
66
67 stop

```

Line 59: `creat_dft_specification`

DFT Specification

- The DFT Specification describes the test hardware that will be added to your design.
 - IJTAG Network configuration
 - Memory BIST partitioning/configuration
- Memory BIST partitioning :**
- Listing of Memory BIST controllers to be generated.
 - Clock domain associated with each memory BIST controller.
 - Memories assigned to each controller.

All the above information will be coming in dft specs.

Creating a New DFT Specification

- A new DFT Specification can be created using the command `create_dft_specification`
- This command uses information from prior settings :
 - `set_design_level`
 - Design netlist etc

For example for IJTAG Network:-

Viewing a DFT Specification

Command : `report_config_data`

```

DftSpecification(corea,first_insertion) {
    IJtagNetwork {
        HostScanInterface(ijtag) {
            Sib(sri) {
                Attributes {
                    tessent_dft_function : scan_resource_instrument_host;
                }
            }
            Tdr(sri_ctrl) {
                Attributes {
                    tessent_dft_function : scan_resource_instrument_dft_control;
                }
            }
        }
        Sib(sti) {
            Attributes {
                tessent_dft_function : scan_tested_instrument_host;
            }
        }
        Sib(mbist) {
        }
    }
}

```



So in IJTAG network 3 SIBS will be created and 1 TDR SRI Control

Inside 3 SIBS

- SIB STI (Scan Tested Instrument)
- SIB SRI (Scan Resource Instrument)
- SIB MBIST - It will only control the MBIST Network

TDR SRI control

- This TDR (As of now it will control the once signal that is entest enable signal) but later in lab3 we will insert some more static signals like memory bypass enable, TCK OCC Enable, MBIST enable,

This are the things will be inserted during IJTAG Network

Viewing a DFT Specification (Cont...)

```
MemoryBist {
    ijtag_host_interface : Sib(mbist);
    Controller(c1) {
        clock_domain_label : clka;
        Step {
            MemoryInterface(m1) {
                instance_name : ram1;
            }
        }
    }
    Controller(c2) {
        clock_domain_label : clkb;
        Step {
            MemoryInterface(m1) {
                instance_name : ram2;
            }
        }
    }
}
```

Memory BIST

Here the clocks of the 2 memories are different.
So they are controlled by 2 different controllers.

In this above code clka is going to ram1 and clkb is going to ram2, that is memory grouping so because of both this stamps having 2 different clocks.

So, both this clocks it has 2 different clocks and 2 different controllers.

```
ANALYSIS> create_dft_specification
//
// Begin creation of DftSpecification(corea,first_insertion)
// Creation of RtlCells wrapper
// Creation of IjtagNetwork wrapper
// Creation of MemoryBist wrapper
// Creation of MemoryBisr wrapper
//
// Done creation of DftSpecification(corea,first_insertion)
//
/DftSpecification(corea,first insertion)
```

```

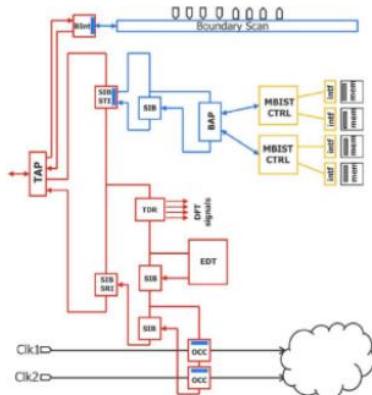
ANALYSIS> report_config_data

DefaultsSpecification(user) {
}
DftSpecification(corea,first_insertion) {
    IjtagNetwork {
        HostScanInterface(ijtag) {
            Sib(sri) {
                Attributes {
                    tesson_dft_function : scan_resource_instrument_host;
                }
                Tdr(sri_ctrl) {
                    Attributes {
                        tesson_dft_function : scan_resource_instrument_dft_control;
                    }
                }
            }
            Sib(sti) {
                Attributes {
                    tesson_dft_function : scan_tested_instrument_host;
                }
                Sib(mbist) {
                }
            }
        }
    }
}
MemoryBist {
    ijtag_host_interface : Sib(mbist);
    Controller(c1) {
        clock_domain_label : clka;
        Step {
            MemoryInterface(m1) {
                instance_name : ram1;
            }
        }
    }
    Controller(c2) {
        clock_domain_label : clkb;
        Step {
            MemoryInterface(m1) {
                instance_name : ram2;
            }
        }
    }
}

```

This the Network which the tool will be created

Diagrammatic Representation of DFT Specification



- A SIB is a special node in IJTAG that acts as a switch.
- Instruments that need to be active during scan (EDT OCC) are inserted under 1 SIB and the ones that are scan tested such as MBIST controller are inserted under another SIB.

Types of SIBs

Scan Tested Instrument (STI): The SIB STI provides access to the IJTAG network for MBIST controller (in this fig).

Scan Resource Instrument (SRI): The SIB SRI provides access to the IJTAG network for logic instruments (EDT, OCC)

Difference between SIB - STI and SIB - SRI

And why are telling as a switch?

- Because It will decide whether to allow or not to allow the data to be return on to the TDR that's why SIB acts as a switch.

Instruments that need to be active during scan they are placed under one SIB and the instruments that has to be scan tested that is MBIST Controller It will be scanned tested and they will be placed under another SIB.

Line 62: It will validate whatever HW it has generated on top and it will insert in our design and it will finally write out all the output files into the TSDB output directory.

Generating and Inserting the Hardware

Command : *process_dft_specification*

- Validates the DFT Specification
- Generates hardware : MBIST related controllers, memory interfaces, IJTAG network
 - RTL and ICL descriptions
- Edits design and inserts generated hardware
- Generates SDC constraints
- Generated files are written into TSDB directory

Line 65: extract_icl

```
ANALYSIS> process_dft_specification
//
// Begin processing of /DftSpecification(corea,first_insertion)
// --- IP generation phase ---
// Validation of IjtagNetwork
// Validation of MemoryBist
// Processing of RtlCells
// Generating Verilog RTL Cells
// Verilog RTL : ../tsdb_outdir/instruments/corea_first_insertion_cells.instrument/corea_first_insertion_
tessent_posedge_synchronizer_reset.v
//
// Loading the generated RTL verilog files (1) to enable instantiating the contained modules
// into the design.
// Processing of IjtagNetwork
// Generating design files for IJTAG SIB module corea_first_insertion_tessent_sib_1
// Verilog RTL : ../tsdb_outdir/instruments/corea_first_insertion_ijtag.instrument/corea_first_insertion_
tessent_sib_1.v
// IJTAG ICL : ../tsdb_outdir/instruments/corea_first_insertion_ijtag.instrument/corea_first_insertion_
tessent_sib_1.icl
// TCD Scan : ../tsdb_outdir/instruments/corea_first_insertion_ijtag.instrument/corea_first_insertion_
tessent_sib_1.tcd_scan
// CTL : ../tsdb_outdir/instruments/corea_first_insertion_ijtag.instrument/corea_first_insertion_
tessent_sib_1.ctl
// TCD : ../tsdb_outdir/instruments/corea_first_insertion_ijtag.instrument/corea_first_insertion_
tessent_sib_1.tcd
// PDL : ../tsdb_outdir/instruments/corea_first_insertion_ijtag.instrument/corea_first_insertion_
tessent_sib_1.pdl
// Generating design files for IJTAG SIB module corea_first_insertion_tessent_sib_2
// Verilog RTL : ../tsdb_outdir/instruments/corea_first_insertion_ijtag.instrument/corea_first_insertion_
tessent_sib_2.v
// IJTAG ICL : ../tsdb_outdir/instruments/corea_first_insertion_ijtag.instrument/corea_first_insertion_
tessent_sib_2.icl
//
// Generating design files for IJTAG SIB module corea_first_insertion_tessent_sib_2
// Verilog RTL : ../tsdb_outdir/instruments/corea_first_insertion_ijtag.instrument/corea_first_insertion_
tessent_sib_2.v
// IJTAG ICL : ../tsdb_outdir/instruments/corea_first_insertion_ijtag.instrument/corea_first_insertion_
tessent_sib_2.icl
// Generating design files for IJTAG SIB module corea_first_insertion_tessent_sib_3
// Verilog RTL : ../tsdb_outdir/instruments/corea_first_insertion_ijtag.instrument/corea_first_insertion_
tessent_sib_3.v
// IJTAG ICL : ../tsdb_outdir/instruments/corea_first_insertion_ijtag.instrument/corea_first_insertion_
tessent_sib_3.icl
// Generating design files for IJTAG Tdr module corea_first_insertion_tessent_tdr_sri_ctrl
// Verilog RTL : ../tsdb_outdir/instruments/corea_first_insertion_ijtag.instrument/corea_first_insertion_
tessent_tdr_sri_ctrl.v
// IJTAG ICL : ../tsdb_outdir/instruments/corea_first_insertion_ijtag.instrument/corea_first_insertion_
tessent_tdr_sri_ctrl.icl
//
// Loading the generated RTL verilog files (4) to enable instantiating the contained modules
// into the design.
// Processing of MemoryBist
// Generating the IJTAG ICL for the memories.
// Generating design files for MemoryBist Controller(c1)
// Generating design files for MemoryBist Controller(c2)
// Warning: There are warnings issued while generating design files for MemoryBist controller(s).
// Review the messages in the following generation log files:
// ..../tsdb_outdir/instruments/corea_first_insertion_mbist.instrument/corea_first_insertion_tessent_mbi
st_c1.generation_log,
// ..../tsdb_outdir/instruments/corea_first_insertion_mbist.instrument/corea_first_insertion_tessent_mbi
st_c2.generation_log
//
// Generating design files for Bist Access Port
//
// Loading the generated RTL verilog files (5) to enable instantiating the contained modules
// into the design.
// Generating design files for MemoryBist controller assemblies
// --- Instrument insertion phase ---
// Inserting instruments of type 'ijtag'
// Inserting instruments of type 'memory_bist'
//
// Writing out modified source design in ..../tsdb_outdir/dft_inserted_designs/corea_first_insertion.dft_insert
ed_design
// Writing out specification in ..../tsdb_outdir/dft_inserted_designs/corea_first_insertion.dft_spec
//
// Done processing of DftSpecification(corea,first_insertion)
//
```

So it was validating the design, whatever DT HW it has generated and it is inserting in our design and it is also writing all the output files into the tsdb output directory so individually for all the sibs, sri control tdr, verilog files and ICL description and even MBIST also, and control it will be creating individually all the three sibs.

```

INSERTION> extract_icl
// Note: Updating the hierarchical data model to reflect RTL design changes.
// Writing design source dictionary : ../tsdb_outdir/dft_inserted_designs/corea_first_insertion.dft_inserted_de
sign/corea.design_source_dictionary
// -----
// Begin RTL synthesis.
// -----
// Synthesized modules=1, Time=1.89 sec.
// Note: There was 1 module selectively synthesized. There were also 5 sub-modules created by synthesis.
//       Use 'get_module -filter is_synthesized' to see them.
//       You can also use 'set_quick_synthesis_options -verbose on' to have the synthesis step report the
//       synthesized module name in the transcript as it is being synthesized.
// -----
// Warning: Rule FN1 violation occurs 1571 times
// Warning: Rule FN4 violation occurs 8 times
// Warning: Rule FP13 violation occurs 26 times
// Flattening process completed, cell instances=962, gates=4823, PIs=77, P0s=65, CPU time=0.07 sec.
// -----
// Begin circuit learning analyses.
// -----
// Learning completed, CPU time=0.00 sec.
// -----
// Begin ICL extraction.
// -----
// ICL extraction completed, ICL instances=11, CPU time=0.10 sec.
// -----
// -----
// Begin ICL elaboration and checking.
// -----
// ICL elaboration completed, CPU time=0.08 sec.
// -----
// Writing ICL file : ../tsdb_outdir/dft_inserted_designs/corea_first_insertion.dft_inserted_design/corea.icl
// Writing consolidated PDL file: ../tsdb_outdir/dft_inserted_designs/corea_first_insertion.dft_inserted_design/
/corea.pdl

// Writing SDC file: ../tsdb_outdir/dft_inserted_designs/corea_first_insertion.dft_inserted_design/corea.sdc
// Writing DFT info dictionary: ../tsdb_outdir/dft_inserted_designs/corea_first_insertion.dft_inserted_design/c
orea.dft_info_dictionary

```

So the ICL, PDL, SDC File all these files will be created.

It will be check in the tsdb output directory

So, corea files will be created.

```

69 /**
70 /**
71 /**
72 /**
73 /**
74 /**
75
76 #create_patterns_spec
77 set spec1 [create_patterns_spec]
78
79 report_config_data $spec1
80
81 ## This will start creating the patterns which are required for mbist/sib network
82 process_patterns_specification
83
84
85 ## This command will prepare the RTL file list to be read in synthesis tool ( DC supportive)
86 write_design_import_script -use_relative_path_to . -replace
87

```

**Line 77: It will create the patterns specs. And what is pattern specs?
It is similar to TCL command.**

```

SETUP> set spec1 [create_patterns_spec]
// sub-command: create_patterns_specification
// Creating '/PatternsSpecification(corea,first_insertion,signoff)'
//   Getting patterns specifications for the 'ijtag' instrument type
//   Getting patterns specifications for the 'memory_bist' instrument type
/PatternsSpecification(corea,first_insertion,signoff)

```

Line 79: Whatever it store into spec1 variable that we will able to see.

\$spec1 means what all are the dollar specifications which has created that we will get in this terminal.

```

SETUP> report_config_data $spec1
PatternsSpecification(corea,first_insertion,signoff) {
    AdvancedOptions {
        ConstantPortSettings {
            scan_en : 0;
        }
    }
    Patterns(ICLNetwork) {
        ICLNetworkVerify(corea) {
        }
    }
    Patterns(MemoryBist_P1) {
        ClockPeriods {
            clk_b : 13.2ns;
            clk_a : 10.0ns;
        }
        TestStep(run_time_prog) {
            MemoryBist {
                run_mode : run_time_prog;
                reduced_address_count : on;
                Controller(corea_first_insertion_tessent_mbist_c1_controller_inst) {
                    DiagnosisOptions {
                        compare_go : on;
                        compare_go_id : on;
                    }
                }
                Controller(corea_first_insertion_tessent_mbist_c2_controller_inst) {
                    DiagnosisOptions {
                        compare_go : on;
                        compare_go_id : on;
                    }
                }
            }
        }
    }
}

```

```

}
Patterns(MemoryBist_ParallelRetentionTest_P1) {
    ClockPeriods {
        clkb : 13.2ns;
        clka : 10.0ns;
    }
    TestStep(ParallelRetentionTest) {
        MemoryBist {
            run_mode : hw_default;
            parallel_retention_time : 0;
            reduced_address_count : on;
            Controller(corea_first_insertion_tessent_mbist_c1_controller_inst) {
                parallel_retention_group : 1;
                DiagnosisOptions {
                    compare_go_id : on;
                }
            }
            Controller(corea_first_insertion_tessent_mbist_c2_controller_inst) {
                parallel_retention_group : 1;
                DiagnosisOptions {
                    compare_go_id : on;
                }
            }
        }
    }
}
-

```

Pattern Specification (Contd...)

reduced_address_count : on ; → Enables the MBIST controller to run on 4 corners of the common memory address space.

This is useful to check the proper functionality of the BIST controller without having to simulate the test for the entire memory space.

This is reduce the run time.

```

TestStep(run_time_prog) {
    MemoryBist {
        run_mode : run_time_prog;
        reduced_address_count : on;
        Controller(corea_first_insertion_tessent_mbist_c1_controller_inst) {
            DiagnosisOptions {
                compare_go : on;
                compare_go_id : on;
            }
        }
    }
}

```

reduced_address_count : on (This is done before manufacturing validation)

Pattern Specification (Contd..)

GO bit indicates whether the controller has passed/failed the simulation.
It indicates the comparator's pass/fail status.

When the test starts, the GO bit starts high and falls when a comparator fails (BIST controller received erroneous response from the memory) and stays low till the end of the test.

At the end of the test,

if GO is 1'b1, it indicates no failing memories
if GO is 1'b0, it indicates detection of failing memories.

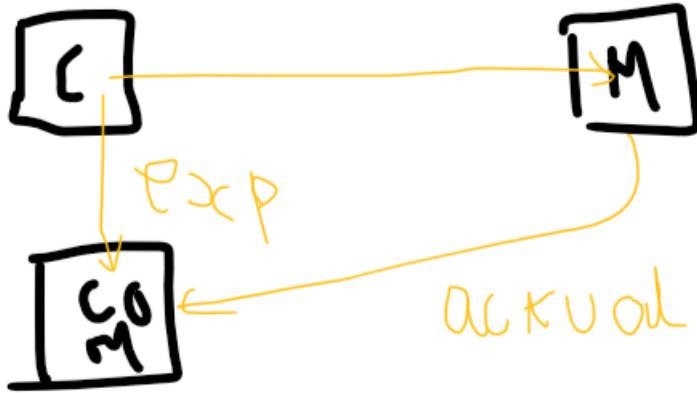
```

TestStep(run_time_prog) {
    MemoryBist {
        run_mode : run_time_prog;
        reduced_address_count : on;
        Controller(corea_first_insertion_tessent_mbist_c1_controller_inst) {
            DiagnosisOptions {
                compare_go : on;           If compare_go is on, then it will check the GO
                compare_go_id : on;        bits.
            }
        }
}

```

FSM and signal which is present inside the controller.

1. so it will write a value memory which is present inside a controller (0 is written onto a memory)
2. Same value will be write it out into a comparator.



3. Output of the memory will be given to the comparator and it will be checked.
 - If both are same, comparator will be expected value and output of the memory will be actual value, then the go bit will be high only.
 - If suppose coupling fault is there in memory, 0 has got change to 1, then we got erroneous message in memory when both these things are compared then go bit will go low and it will stay low throughout the test.

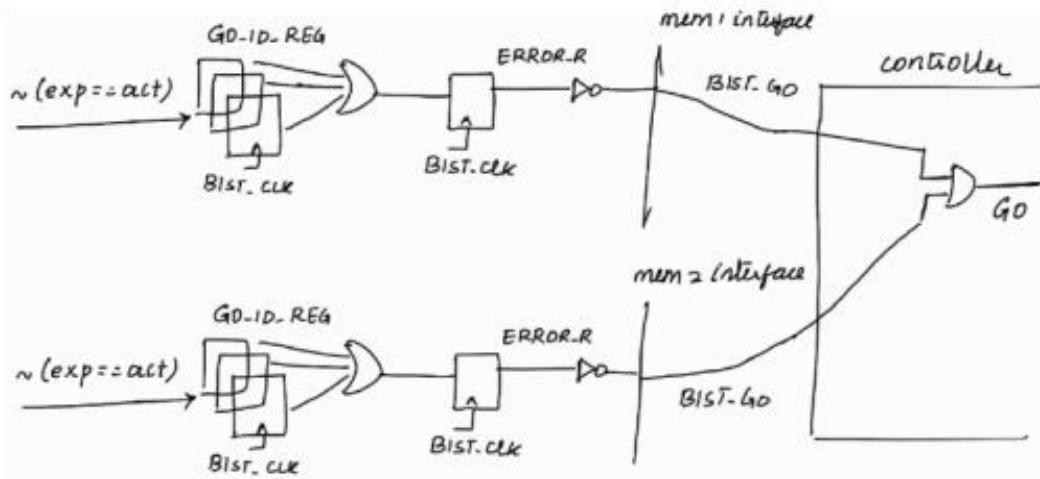
Pattern Specification (Contd..)

When compare_go_id is set to on, we can directly get from the simulation logfile the failing controllers, the ICL and design instance of the memory interface and go_id_reg of the failing memory.

When compare_go_id is set to off, the only information which we get from the simulation logfile is the failing controller.

```
TestStep(run_time_prog) {
    MemoryBist {
        run_mode : run_time_prog;
        reduced_address_count : on;
        Controller(corea_first_insertion_tessent_mbist_c1_controller_inst) {
            DiagnosisOptions {
                compare_go : on;
                compare_go_id : on;
            }
        }
    }
}
```

- If some memories are failing then the simulation log file will tell which controller is failing and then ICL and design instance of the memory interface and go id ref of the failing memory, if compare go id is turned on.



- Expected value is written to the comparator, and actual value from the memory that is actual patterns that is output value from the memory $\sim(\text{exp} == \text{act})$ it's a relational operator
- The number of bits of the go id reg it will be equal to the number of dout in the memory.
- If a single controller it is controlling more than one memory where it will be there in memory grouping concept, the BIST_GO which is specific for 1st memory and for 2nd memory again I will be having another BIST_GO, so this two things, it will inside the controller it will be added and the output will be GO

Line 82: It will validate all the patterns specifications and it will finally write out the TB and patterns files into the tsdb output directory/patterns directory.

```

SETUP> process_patterns_specification
//
// Begin processing of /PatternsSpecification(corea,first_insertion,signoff)
//
// Processing of /PatternsSpecification(corea,first_insertion,signoff)/Patterns(ICLNetwork)
//
// Creation of pattern 'ICLNetwork'
// Solving ICLNetworkVerify(corea)
//
// Writing pattern file '../tsdb_outdir/patterns/corea_first_insertion.patterns_signoff/ICLNetwork.v'
//
// Processing of /PatternsSpecification(corea,first_insertion,signoff)/Patterns(MemoryBist_P1)
// Processing of TestStep(run_time_prog) instrument 'memory_bist'
//
// Creation of pattern 'MemoryBist_P1'
// Solving TestStep(run_time_prog)
//
// Writing pattern file '../tsdb_outdir/patterns/corea_first_insertion.patterns_signoff/MemoryBist_P1.v'
//
// Processing of /PatternsSpecification(corea,first_insertion,signoff)/Patterns(MemoryBist_ParallelRetentionTest_P1)
// Processing of TestStep(ParallelRetentionTest) instrument 'memory_bist'
//
// Creation of pattern 'MemoryBist_ParallelRetentionTest_P1'
// Solving TestStep(ParallelRetentionTest)
//
// Writing pattern file '../tsdb_outdir/patterns/corea_first_insertion.patterns_signoff/MemoryBist_ParallelRetentionTest_P1.v'
// Writing simulation data dictionary file '../tsdb_outdir/patterns/corea_first_insertion.patterns_signoff/simulation.data_dictionary'
//
// Done processing of /PatternsSpecification(corea,first_insertion,signoff)
//
// Writing configuration data file '../tsdb_outdir/patterns/corea_first_insertion.patterns_spec_signoff'.

```

Line 86: After MBIST Insertion we are not having here EDT and OCC insertion, directly we will do synthesis, then tool will directly write out the RTL file list which has to be read into the synthesis whichever files has to be inputs of synthesis that will be automatically written out by the tool.

```
SETUP> write_design_import_script -use_relative_path_to . -replace  
// Writing file 'corea.dc_shell_import_script'.
```

```

87
88 #//
89 #//
90 #//
91 #//
92 #//
93 #//
94
95
96 ## We can invoke the simulation tool via mentor tessent inorder to perform simulations in same shell/session.
97
98 ## if we want to provide any additional library files which are in verilog format that are supported in simulator
99 set_simulation_library_sources -v ../../library/adk.v -y ../../library/mems -extension v
100
101 report_simulation_library_sources
102
103 ## This command will create the setup/compilation/simulation command files automatically supported by all tools and also
     executes them
104 #run_testbench_simulations -<options> ; default it will write questa supportive files
105 run_testbench_simulations
106

```

Line 99: Whichever the library file we want to read during simulation time i.e. adk.v library file we are reading and then inside this mems directory whichever having file is .v extension inside the mems directory those files will be read that is the verilog file of the memory.

Line 101: Whatever the library it has been read that will be displayed here.

```

SETUP> set_simulation_library_sources -v ../../library/adk.v -y ../../library/mems -extension v
SETUP> report_simulation_library_sources
//                                         file extensions
// List of -v/-y files and directories
// type path                               -----
// -----                                 -----
// file  ../../library/adk.v               v
// dir   ../../library/mems               v.gz
// file  /home/tools/mentor/MENTOR SOURCE/lnx-x86/lib64/hdlang/lib/dft sim.v

```

Inside the mems, whatever having the .v extension those files will be read. It describes the functionality of the memory

Line 105: run test bench simulations

- It will automatically do the sims scripts and it will tell the status

```

SETUP> run_testbench_simulations
Starting 3 simulations for ./simulation_outdir/corea_first_insertion.simulation_signoff
// Waiting for the simulation(s) to complete

unscheduled 0 queued 0 running 0 pass 3 fail 0

```

The 3 simulations are:

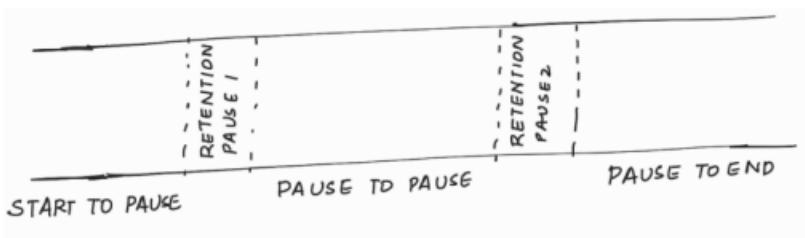
- One is to validate the IJTAG-ICL network
- One is to validate the MBIST network
- One is to validate the Memory Retention Test Network

So all the simulations has been passed

RETENTION TEST

Retention Test is done to check if the memory cells are able to retain the value for some time.
So instead of reading immediately after a cell is written, we pause it for some time and then read the memory.

Step	Event	Library Algorithm Phase Execution
1	Load checkerboard background	start_to_pause
2	Apply first retention pause	n/a
3	Read checkerboard background. Load inverse checkerboard background.	pause_to_pause
4	Apply second retention pause	n/a
5	Read inverse checkerboard background	pause_to_end



Step 1: Start to pause phase: tool will load the checkerboard algorithm, It means alternatively 0's and 1's will be return.

Step 2: Apply first retention pause

Step 3: Whatever the checkerboard pattern is written here that will be read, and the inverse checkerboard pattern will be loaded. Like 1st for Black Cells in station it is representing like 1 is written then all white cells 0 is written that is checkerboard pattern.

Inverse Checkerboard pattern it is just the opposite that is black cells 0 will be written, and for white cells 1 will be written.

Step 4: Apply second retention pause

Step 5: Inverse checkerboard pattern will be read.

- So this is what happens in memory retention test. This is retention test, to check if the memory cells we are able to retain the value for sometime or not. So instead of reading the memory immediately after it has written we will read the memory after some time.
- So write the memory pause it for sometime and afterwards will read the memory.

Extracting the ICL:-

```
64 ## Till above command, tool will be in insertion state, giving below command will make the tool to shift to
    setup state
65 extract_icl
66
67 stop
```

To get the complete path

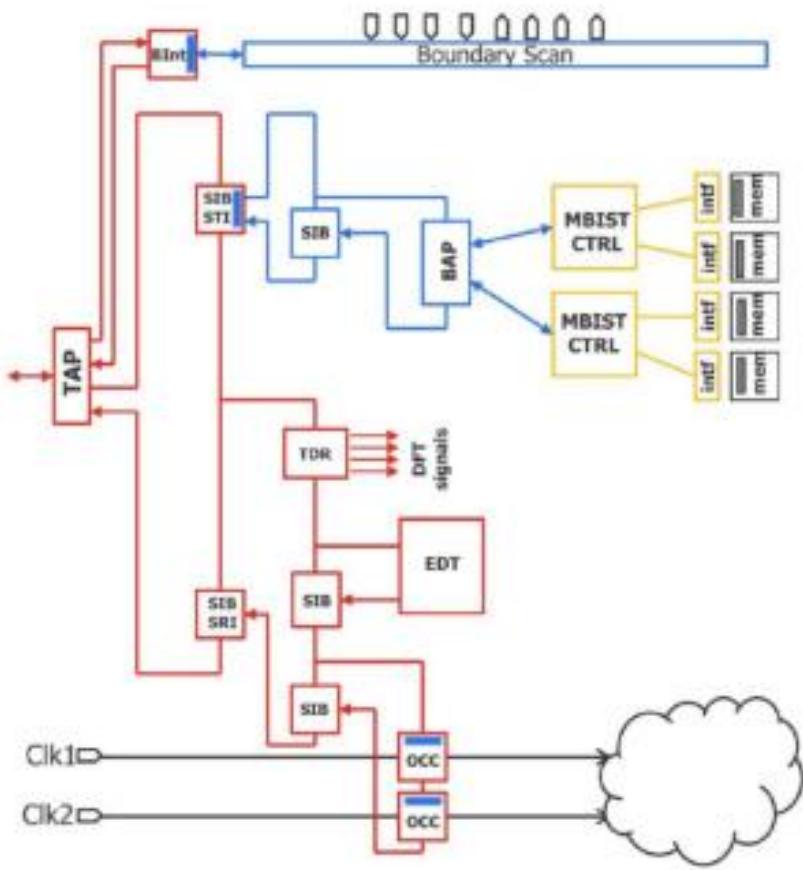
```
SETUP> get_instance *sib* -hier
{corea_first_insertion_tessent_sib_mbist_inst corea_first_insertion_tessent_sib_sri_inst corea_first_insertion_t
esson_sib_sti_inst corea_first_insertion_tessent_mbist_bap_inst/corea_first_insertion_tessent_mbist_controller_
sib_ctl_bypass_inst corea_first_insertion_tessent_mbist_bap_inst/corea_first_insertion_tessent_mbist_controller_
sib_inst0 corea_first_insertion_tessent_mbist_bap_inst/corea_first_insertion_tessent_mbist_controller_sib_inst1
corea_first_insertion_tessent_mbist_bap_inst/corea_first_insertion_tessent_mbist_controller_sib_tdr_bypass_inst}
```

Add schematic objects in 2021 version and it was similar to add display instances in the 2016
tessent version

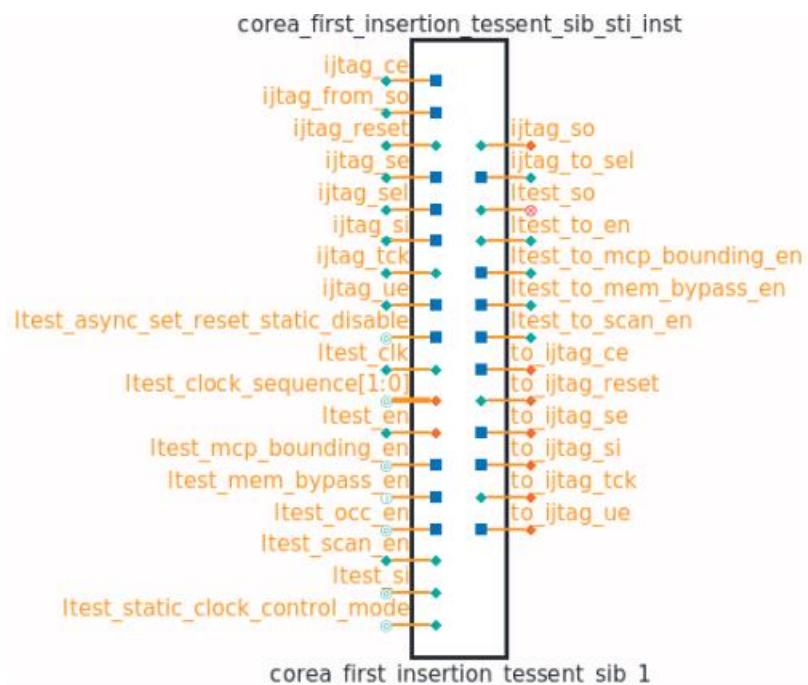
```
SETUP> a_s_o corea_first_insertion_tessent_sib_sti_inst -disp hier
```

corea_first_insertion_tessent_sib_sti_inst

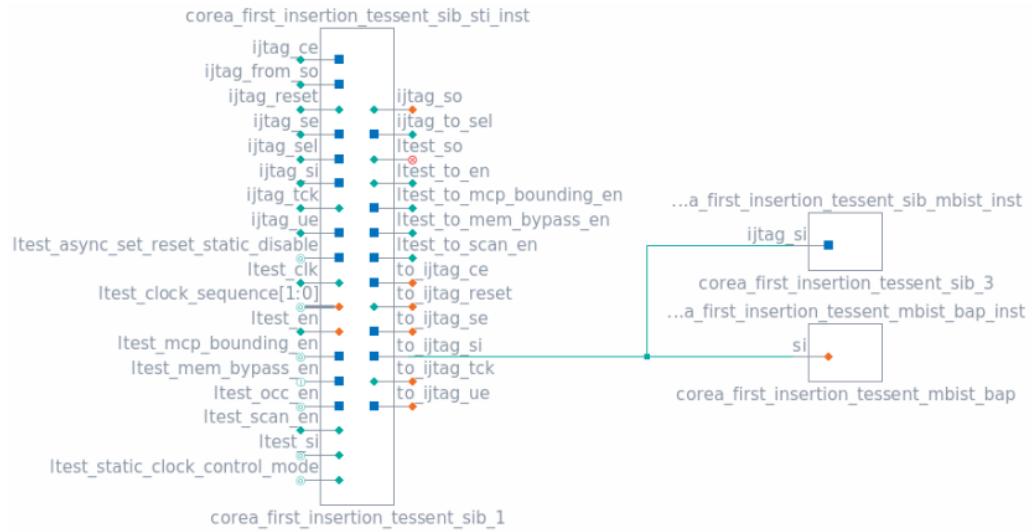
corea_first_insertion_tessent_sib_1



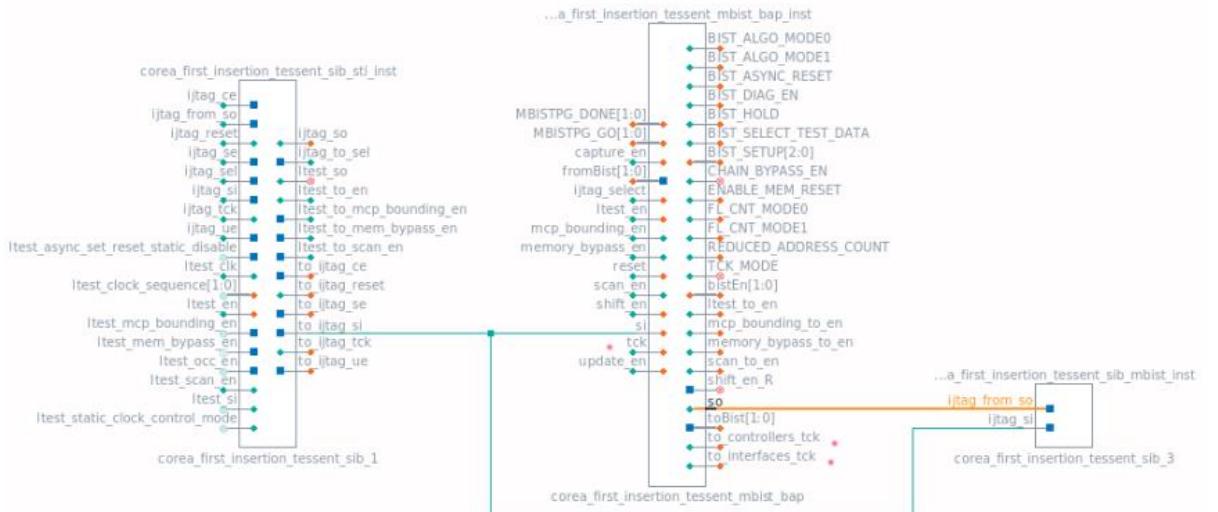
```
SETUP> a_s_o corea_first_insertion_tessent_sib_sti_inst -disp hier
```



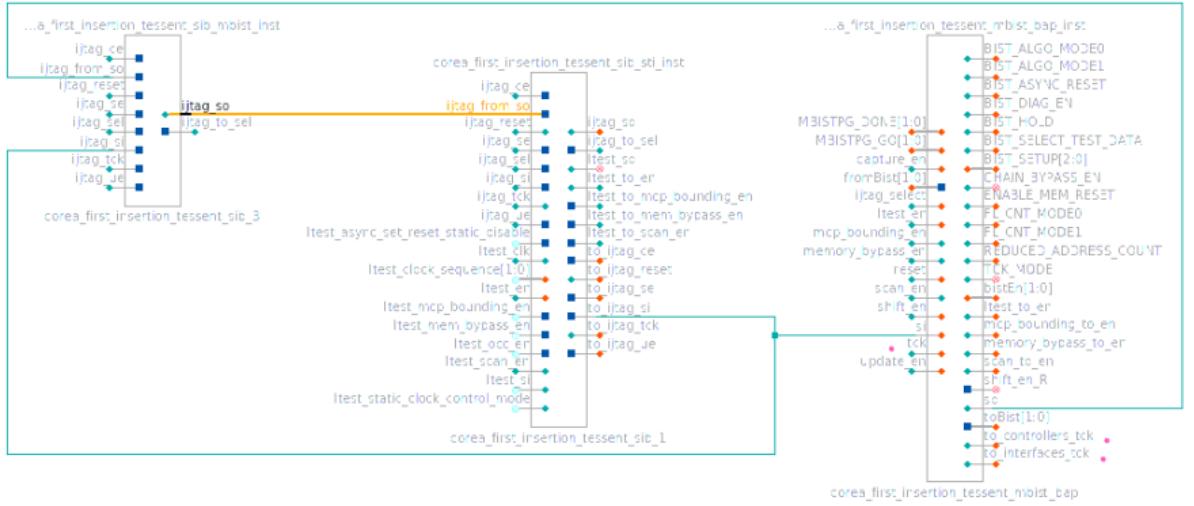
1. IJTAG to SI it will be going to SIB MBIST and another fanout will be going to BAP



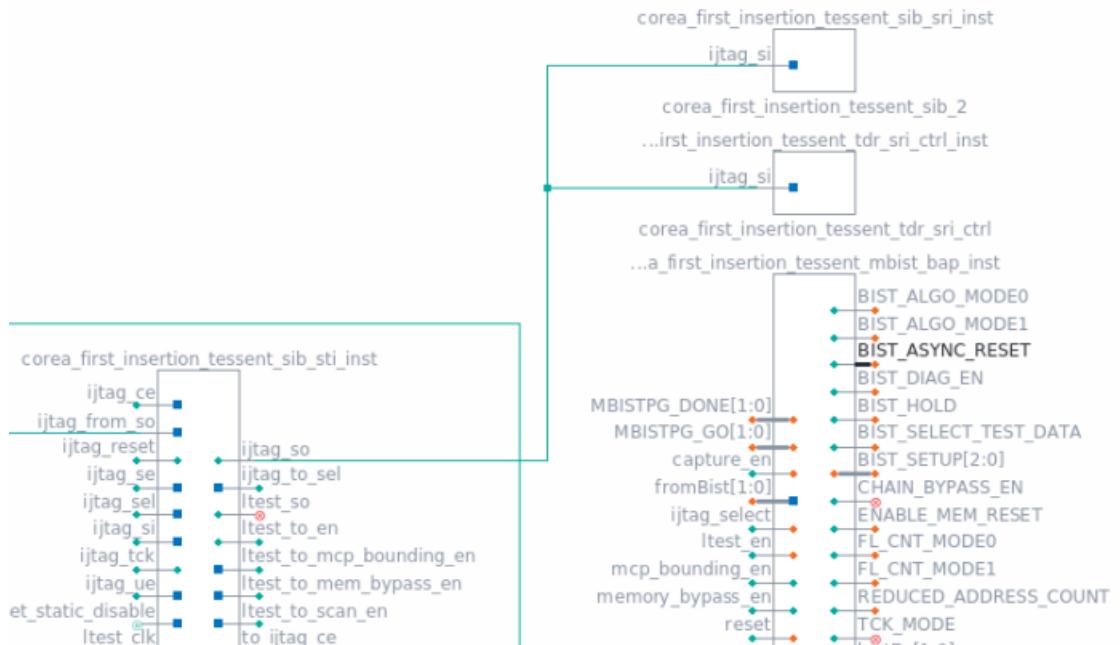
2. BAPS output it will got SIB MBIST



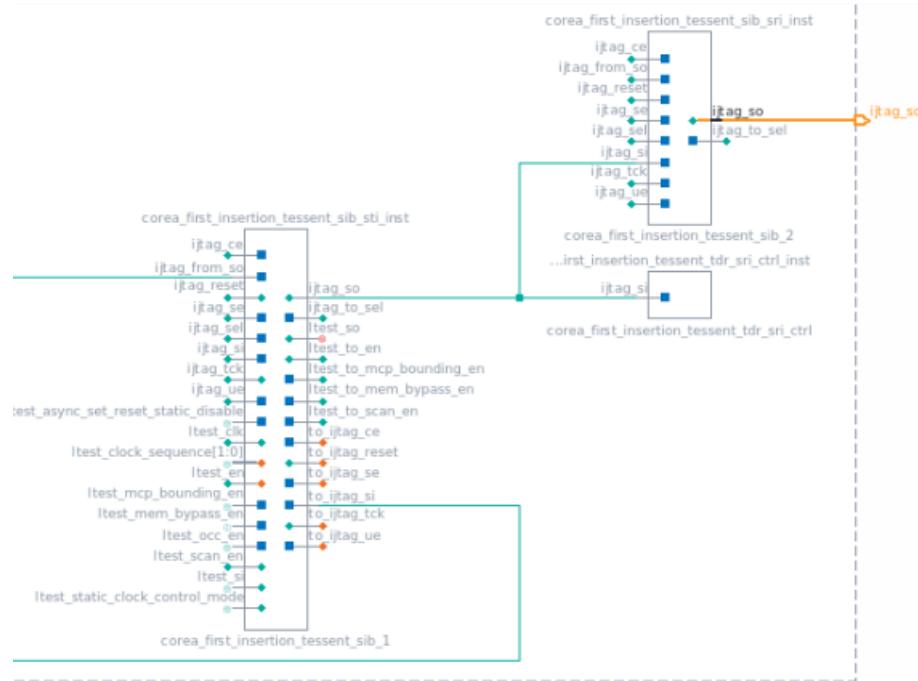
3. SIB MBIST it will go SIB STI



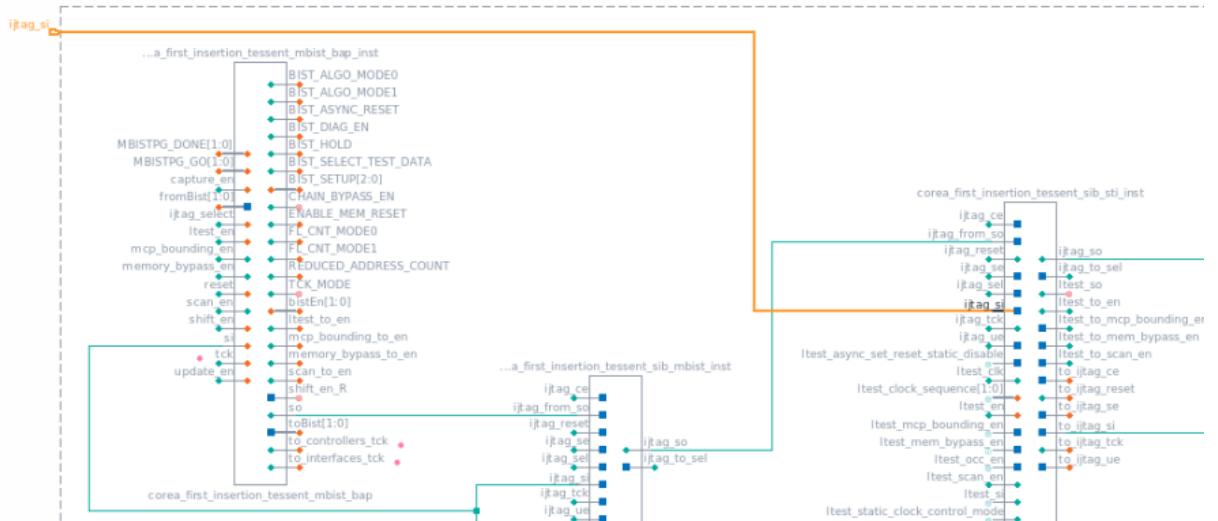
4. SIB STI Output will go SIB SRI and another fanout will go to TDR



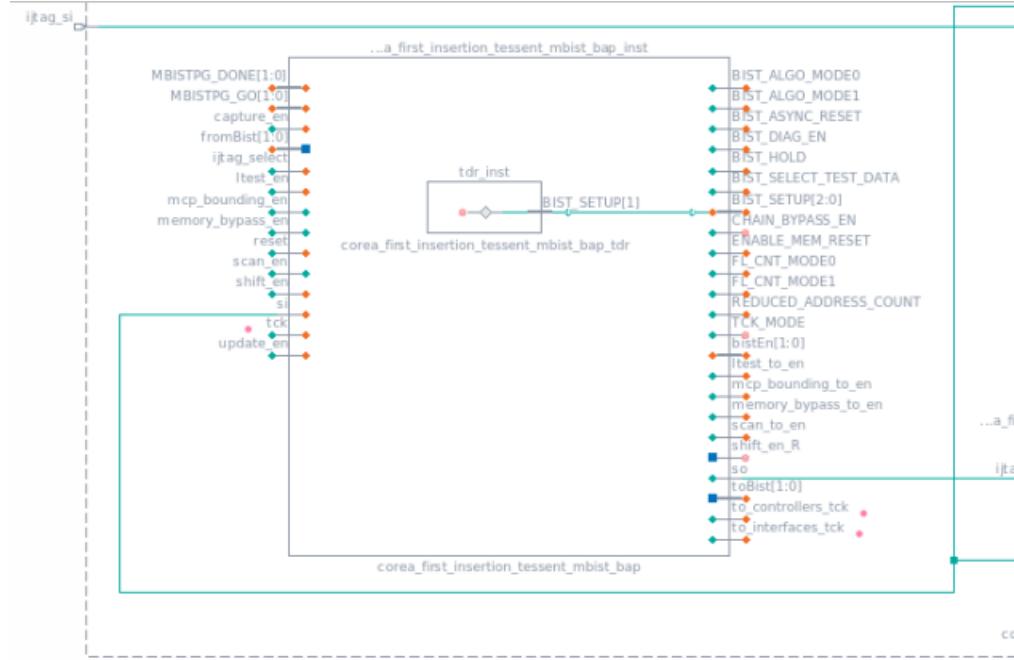
5. SIB SRI output will go to Top level Port, but later if we go in COREB level it will controlled by another SIB



6. SIB STI Input is coming from IJTAG Design which is a TOP level port but later if we go for COREB level, it will be controlled by another SIB.



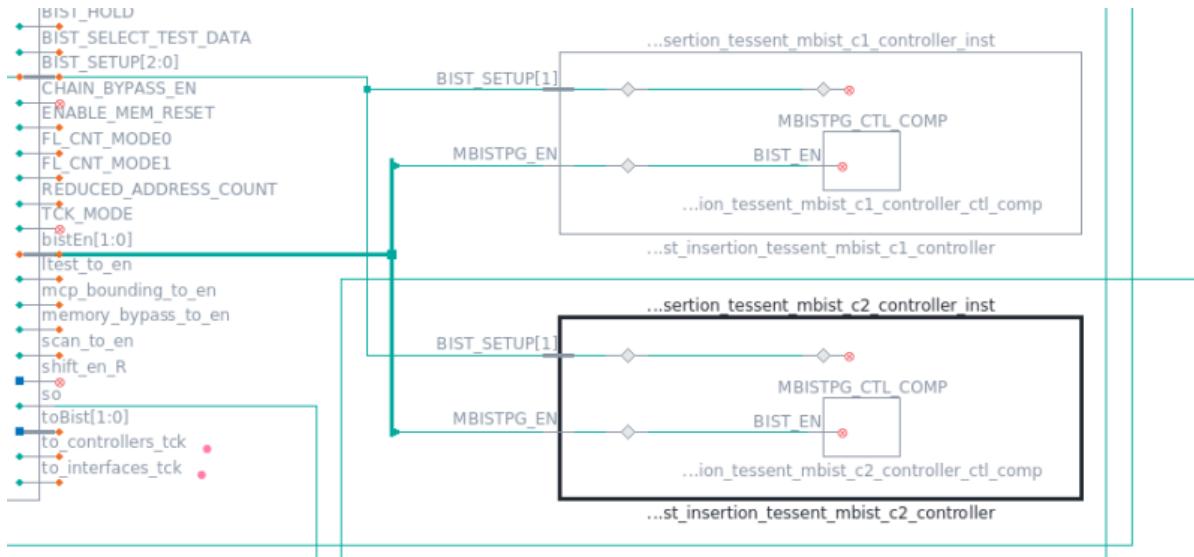
7. Inside the BAP it has a TDR logic, so the output of BAP will be controlling the signals
- It requires MBIST PG Enable, MBIST Setup signal, these signals has to be controlled in order to start the MBIST operation, these signals will be controlled by BAP so it has TDR inside a BAP that will be controlling the signals.



- BIST setup signals will be going to the controller C1 and C2

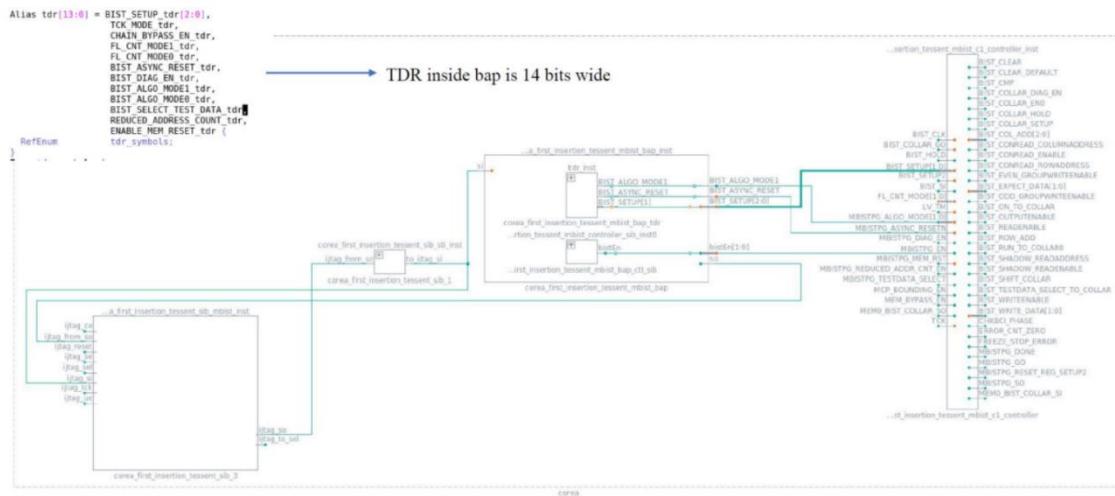


8. BIST Enable signal will be controlling the controller C1 and controller C2, so these signals are necessary for initiating the test,
- So BIST setup has to be 1 0 and MBISTPG_EN has to be 1
 - BIST_SETUP will be controlled by BAP
 - MBISTPG_EN will be going to the input of the controller.



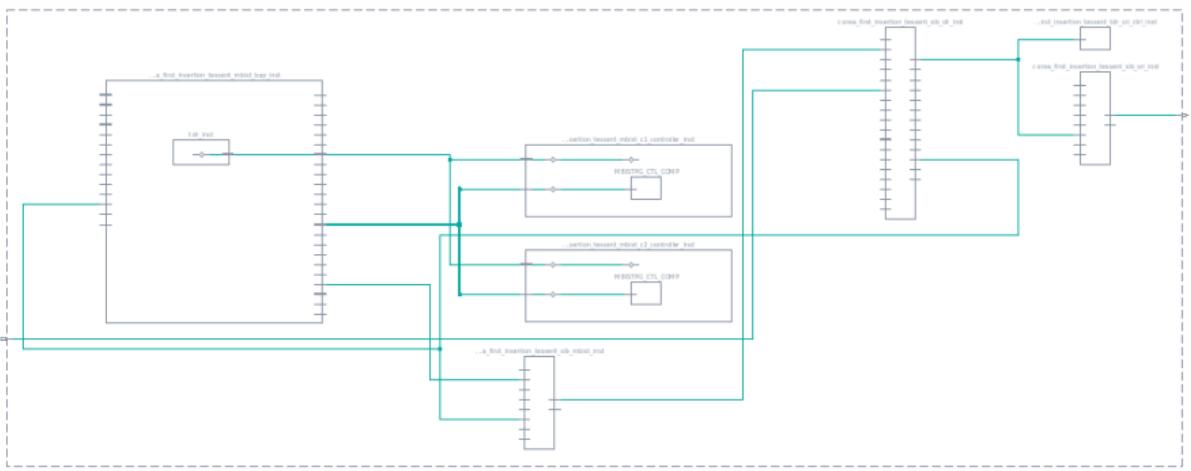
9.BAP will be controlling 14 other signals.

- TDR which is present inside the BAP

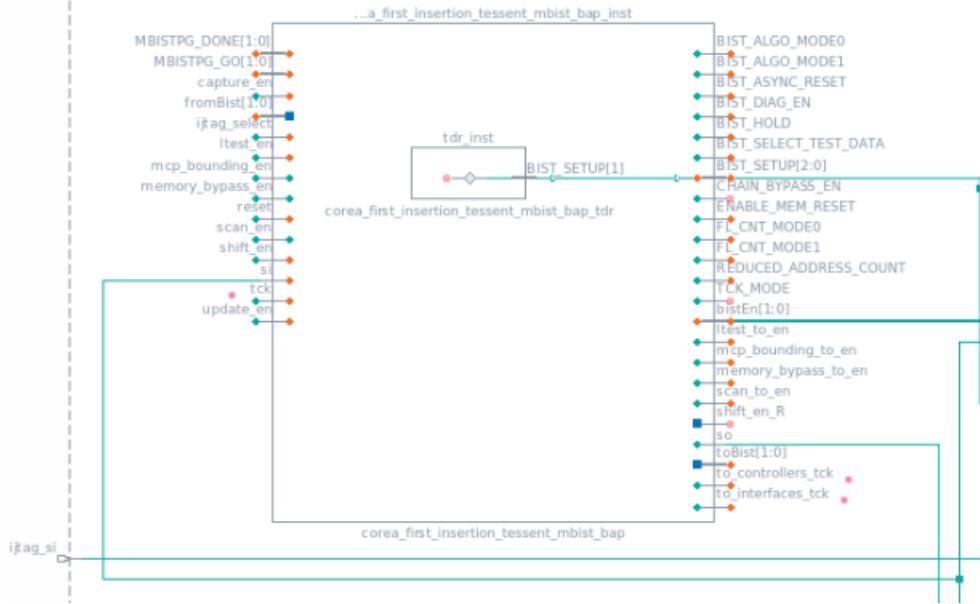


source schematic_ijtag_network.tcl to see it in the future purpose when we use it.

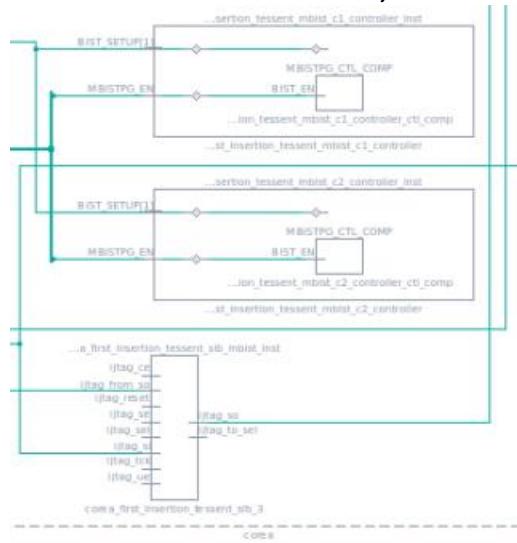
Hierarchical Schematic for COREA:-



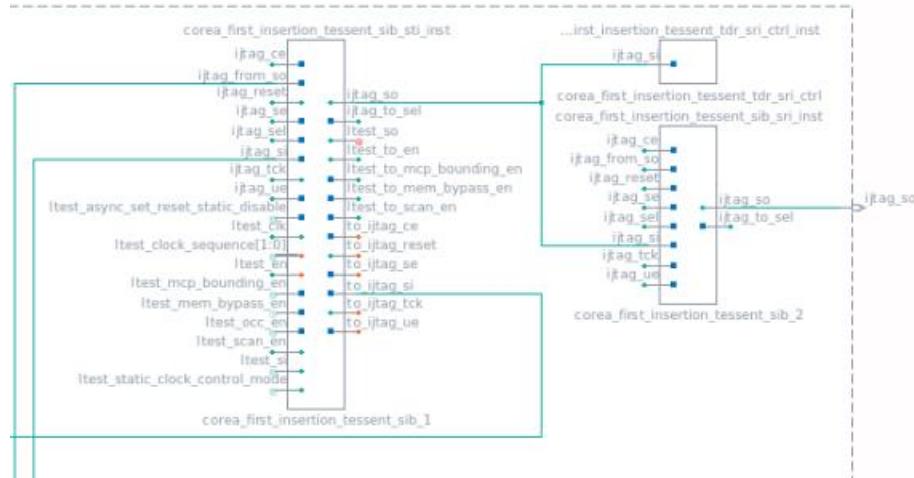
1. MBIST BAP



2. MBIST C1 and C2 Controllers, and MBIST SIB



3. SIB STI, TDR SRI and SIB - 2



DFT INSERTED DESIGNS:-

```
/home/vinayakp/aug23/level3/Lab0>>ll
total 4
drwxr-xr-x. 3 vinayakp vinayakp 16 Dec 22 12:22 atpg
drwxr-xr-x. 2 vinayakp vinayakp 21 Dec 22 12:22 design
drwxr-xr-x. 3 vinayakp vinayakp 4096 Dec 23 10:48 mbist_insertion
drwxr-xr-x. 2 vinayakp vinayakp 52 Dec 22 12:22 scan_insertion
drwxr-xr-x. 3 vinayakp vinayakp 93 Dec 22 12:22 synthesis
drwxr-xr-x. 6 vinayakp vinayakp 93 Dec 22 12:22 tsdb_outdir
/home/vinayakp/aug23/level3/Lab0>>cd tsdb_outdir/
/home/vinayakp/aug23/level3/Lab0/tsdb_outdir>>ls
dft_inserted_designs instruments logic_test_cores patterns
/home/vinayakp/aug23/level3/Lab0/tsdb_outdir>>cd dft_inserted_designs/
/home/vinayakp/aug23/level3/Lab0/tsdb_outdir/dft_inserted_designs>>ls
corea_corea_scan.dft_inserted_design corea_first_insertion.dft_inserted_design corea_first_insertion.dft_spec
/home/vinayakp/aug23/level3/Lab0/tsdb_outdir/dft_inserted_designs>>ll
total 4
drwxr-xr-x. 2 vinayakp vinayakp 142 Dec 22 12:22 corea_corea_scan.dft_inserted_design
drwxrwxr-x. 3 vinayakp vinayakp 275 Dec 23 10:46 corea_first_insertion.dft_inserted_design
-rwxr-xr-x. 1 vinayakp vinayakp 1096 Dec 23 10:46 corea_first_insertion.dft_spec
/home/vinayakp/aug23/level3/Lab0/tsdb_outdir/dft_inserted_designs>>cd corea_first_insertion.dft_inserted_design
/home/vinayakp/aug23/level3/Lab0/tsdb_outdir/dft_inserted_designs/corea_first_insertion.dft_inserted_design>>ll
total 320
-rw-rw-r--. 1 vinayakp vinayakp 2355 Dec 23 10:46 corea.design_source_dictionary
-rw-rw-r--. 1 vinayakp vinayakp 1749 Dec 23 10:46 corea.dft_info_dictionary
-rw-rw-r--. 1 vinayakp vinayakp 4277 Dec 23 10:46 corea.dft_summary_dictionary
-rw-rw-r--. 1 vinayakp vinayakp 49301 Dec 23 10:46 corea.icl
-rw-rw-r--. 1 vinayakp vinayakp 56285 Dec 23 10:46 corea.pdl
-rw-rw-r--. 1 vinayakp vinayakp 186039 Dec 23 10:46 corea.sdc
-rw-rw-r--. 1 vinayakp vinayakp 1115 Dec 23 10:46 corea.tcd
-rw-rw-r--. 1 vinayakp vinayakp 678 Dec 23 10:46 corea.tsdb_info
lrwxrwxrwx. 1 vinayakp vinayakp 28 Dec 23 10:46 corea.v_full -> ./modified_rtl_files/corea.v
-rw-rw-r--. 1 vinayakp vinayakp 545 Dec 23 10:46 corea.v_interface
drwxrwxr-x. 2 vinayakp vinayakp 21 Dec 23 10:46 modified_rtl_files
/home/vinayakp/aug23/level3/Lab0/tsdb_outdir/dft_inserted_designs/corea_first_insertion.dft_inserted_design>>ll
```

1. ICL File

Instrument Connectivity Language (ICL)

- Language used to describe test instruments and their access network.
- ICL is not a complete netlist. It only consists of abstract information required to navigate the instrument access network.

Interconnection between the components

```
Instance corea_first_insertion_tessent_mbist_bap_inst Of
  corea_first_insertion_tessent_mbist_bap {
    InputPort reset =
      corea_first_insertion_tessent_sib_sti_inst.to_ijtag_reset;
    InputPort ijtag_select =
      corea_first_insertion_tessent_sib_mbist_inst.ijtag_to_sel;
    InputPort si = corea_first_insertion_tessent_sib_sti_inst.to_ijtag_si;
    InputPort capture_en =
      corea_first_insertion_tessent_sib_sti_inst.to_ijtag_ce;
    InputPort shift_en =
      corea_first_insertion_tessent_sib_sti_inst.to_ijtag_se;
    InputPort update_en =
      corea_first_insertion_tessent_sib_sti_inst.to_ijtag_ue;
    InputPort tck = corea_first_insertion_tessent_sib_sti_inst.to_ijtag_tck;
    InputPort memory_bypass_en =
      corea_first_insertion_tessent_sib_sti_inst.ltest_to_mem_bypass_en;
    InputPort mcp_bounding_en =
      corea_first_insertion_tessent_sib_sti_inst.ltest_to_mcp_bounding_en;
    InputPort ltest_en =
      corea_first_insertion_tessent_sib_sti_inst.ltest_to_en;
    InputPort fromBist[1] =
      corea_first_insertion_tessent_mbist_c2_controller_inst.MBISTPG_S0;
    InputPort fromBist[0] =
      corea_first_insertion_tessent_mbist_c1_controller_inst.MBISTPG_S0;
    InputPort MBISTPG_GO[1] =
      corea_first_insertion_tessent_mbist_c2_controller_inst.MBISTPG_G0;
```

2. PDL File

Procedural Description Language (PDL)

- PDL provides a way to define procedures to operate an instrument.
- PDL is a sequence of commands that are a set of stimuli and expected responses that are applied on the interface of an instrument.
 - **iWrite** : Stimuli to the instrument are specified by iwrite.
 - Ex: iWrite Block1.MyTdr.R 8b00000101
 - In this example, the register R, an object in ICL instance MyTdr that is instantiated in instance Block1, is loaded with a value of 8b00000101
 - **iRead** : Expected responses are specified with the command iRead.
 - Ex: iRead Block1.MyTdr.R 0b0101
 - In this example, if R is an 8 bit wide register, then the compare value is zero padded to 0b00000101
- iWrite Block1.MyTdr.R 8b00000101
The value (8b00000101) will be written onto this TDR (Block1.MyTdr.R)
 - iRead Block1.MyTdr.R 0b0101
The expected response (0b0101) is being specified by iRead command
The value from this TDR (Block1.MyTdr.R) it should be this value (0b0101) which is expected value.

```
112 # [end]  : Setup Phase }}}
113 # [start] : Run phase {{{
114     set apply_run_phase yes
115     if { $apply_run_phase } {
116         iTake ${controller_instance}.BIST_SETUP[1]
117         iWrite ${controller_instance}.BIST_SETUP[1] 1
118         iWrite ${controller_instance}.RUN_MODE HWDefault
119         iApply
120         iRunLoop 1 -tck
121         set check_go_pre_exec 1
122         set check_done_pre_exec 1
123         if { [regexp -nocase {pause _to _pause} $retention_test_phase ] || [regexp -nocase {pause _to _end} $retention_te
t_phase ] } {
124             set check_go_pre_exec 0
125             set check_done_pre_exec 0
126         }
127         if { $check_go_pre_exec } {
128             if { $compare_go } {
129                 iNote "Checking GO is FAIL before execution"
130                 iNote "tesson_pragma optional_iRead"
131                 iRead ${controller_instance}.MBISTPG_GO Fail
132             }
133         }
134         if { $check_done_pre_exec } {
135             iNote "Checking DONE is FAIL before execution"
136             iNote "tesson_pragma optional_iRead"
137             iRead ${controller_instance}.MBISTPG_DONE Fail
138     }
```

```

139      iTake ${controller_instance}.MBISTPG_EN
140      iWrite ${controller_instance}.MBISTPG_EN 1
141      iNote "Starting MemoryBist controller execution : ${controller_instance}"
142      if { $bap_instance ne "" } {
143          iWrite ${bap_instance}.CHAIN_BYPASS_EN 1
144          iTake ${bap_instance}.CHAIN_BYPASS_EN
145      }
146      iApply
147      iRunLoop 1 -tck
148      iEvent corea_first_insertion_tessent_mbist_cl_controller_start_execution
149      if {$clock_source eq "tck"} {
150          iRunLoop [expr $run_length+5] -tck
151      } else {
152          iRunLoop [expr $run_length+5] -sck ${controller_instance}.BIST_CLK
153      }
154      set check_go_post_exec 1
155      set check_done_post_exec 1
156      if { $check_go_post_exec } {
157          if { $compare_go } {
158              iNote "Checking GO is PASS after execution completion"
159              iRead ${controller_instance}.MBISTPG_GO Pass
160          }
161      }
162      if { $check_done_post_exec } {
163          iNote "Checking DONE is PASS after execution completion"
164          iRead ${controller_instance}.MBISTPG_DONE Pass
165      }
166      iWrite ${controller_instance}.MBISTPG_EN 0
167      iEvent corea_first_insertion_tessent_mbist_cl_controller_stop_execution
168      iApply
169      if { $bap_instance ne "" } {
170          iRelease ${bap_instance}.CHAIN_BYPASS_EN
171      }
172      iRelease ${controller_instance}.MBISTPG_EN
173      iRelease ${controller_instance}.BIST_SETUP[1]
174  }

```

Go bit and Done bit should be zero

so before execution the starting of the test, the go bit and done bit has to be zero

Line 129: The iNote which is comments, so it is checking whether go bit fail before execution

So iRead is fail then it has to be zero

And same goes for done so before execution done bit has to be zero

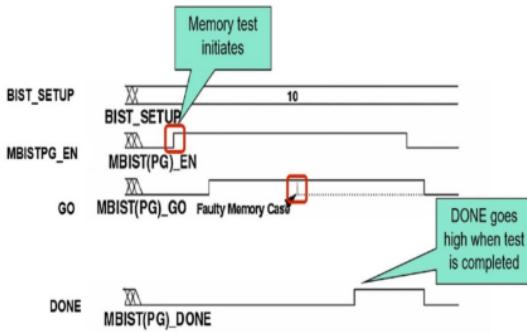
Line 140: iWrite - here we have to make MBISTPG_EN 1 only then the test will be starting

After MBIST is done, we are checking the go bits, the expected values of go and done bits should be 1

Go bit is 1 which means there is no error in the memory .

Done bit is 1 when the test is completed.

TESSENT MBIST OPERATING PROTOCOL



- Memory Test is initiated when MBISTPG_EN signal is high and 2 bits of BIST_SETUP is 10.
- If an error is found during test, the GO signal goes low and stays low during the remaining test.
- When the test is completed, the DONE signal goes high.

DONE	GO	
1	1	The memory BIST test ran to completion and passed
1	0	The memory BIST controller completed the test, but one of the memories being tested failed

- So before execution both go and done bit are zero, then the test is started go bit will be high and it will remain high till the test has completed, if no error is found
- If suppose if any faulty memory is there that is expected value and actual value
- Expected value which is written onto a comparator
- So the expected value and output from the memory if both are different that is faulty memory case then the go bit will go low and it will stay low during the remaining test and done bit it will be equal to high when the test is completed.
- Therefore, before execution both go and done bit should be zero ... MBISTPG_EN will be made 1 and after execution go and done bit expected value should be 1

From line 131 and 137: iRead - Before execution we are checking whether go bit and done bit is failing where both are 0.

From line 140: iWrite - We are writing i.e. MBISTPG_EN to 1 where it should be made as 1.

From line 159 and 164: iRead - means this is the expected value, we are checking whether go bit and done bit has passed which is After execution.

3. SDC(Synopsys Design Constraints) File

- In sdc file we will be having information about the clock, FP, MCP

```

proc tessent_create_functional_clocks {} {
  global time_unit_multiplier tessent_clock_mapping tessent_unmapped_functional_clocks
  create_clock [tessent_get_ports [list {clka}]] \
    -period [expr 10.0*$time_unit_multiplier] \
    -name $tessent_clock_mapping(clka)

  create_clock [tessent_get_ports [list {clkb}]] \
    -period [expr 13.2*$time_unit_multiplier] \
    -name $tessent_clock_mapping(clkb)

  set tessent_unmapped_functional_clocks [lsort -unique [concat $tessent_unmapped_functional_clocks [list clka clkb]]]
}

```

```

set_false_path -from [tessent_get_ports [list {ijtag_reset}]]
set_multicycle_path -setup 2 \
    -from [tessent_get_ports [list {ijtag_sel}]]■
set_multicycle_path -hold 2 \
    -from [tessent_get_ports [list {ijtag_sel}]]■
set_input_delay $local_input_delay -clock $tessent_clock_mapping(tessent_tck) [tessent_get_ports {ijtag_ce}] -clock_fall
set_input_delay $local_input_delay -clock $tessent_clock_mapping(tessent_tck) [tessent_get_ports {ijtag_se}] -clock_fall
set_input_delay $local_input_delay -clock $tessent_clock_mapping(tessent_tck) [tessent_get_ports {ijtag_ue}] -clock_fall
set_input_delay $local_input_delay -clock $tessent_clock_mapping(tessent_tck) [tessent_get_ports {ijtag_sel}] -clock_fall
set_input_delay $local_input_delay -clock $tessent_clock_mapping(tessent_tck) [tessent_get_ports {ijtag_si}] -clock_fall
set_output_delay $local_output_delay -clock $tessent_clock_mapping(tessent_tck) [tessent_get_ports {ijtag_so}] -clock_fall

set scan_resource_sib_list {
    corea_first_insertion_tessent_sib_sri_inst/to_enable_int*
    corea_first_insertion_tessent_sib_sti_inst/to_enable_int*
}
set_multicycle_path -setup 2 \
    -from [tessent_get_cells $scan_resource_sib_list]
set_multicycle_path -hold 2 \
    -from [tessent_get_cells $scan_resource_sib_list]
}

```

4. TCD(Tessent Core Description) File

- It has information about the sub block, that is information about the corea

```

8 Core(corea) {
9     DesignInfo {
10     design_id : first_insertion;
11     design_level : physical_block;
12     ChildBlockModules {
13     }
14     Clocks {
15         Clock(clka) {
16             domain_label : clka;
17             type : async_source;
18             base_period : 10.00ns;
19             period : 10.0;
20         }
21         Clock(clkb) {
22             domain_label : clkb;
23             type : async_source;
24             base_period : 13.20ns;
25             period : 13.2;
26         }
27         Clock(test_clock) {
28             domain_label : test_clock;
29             type : sync_source;
30         }
31     }
32     DynamicDftSignals {
33         DynamicDftSignal(scan_en) {
34             Instance {
35                 type : port;
36                 add_hold_scan_cell : off;
37                 node_name : scan_en;
38             }
39         }
40         DynamicDftSignal(shift_capture_clock) {
41             Instance {
42                 type : port;
43                 add_hold_scan_cell : off;
44                 node_name : test_clock;
45             }
46         }
47     }
48 }
49 }

```

- The dynamic signals that we have added that is Scan enable and shift capture clock which is controlled from top level port.

5. corea.dft_summary_dictionary

```
9 set dft_summary {
10   corea {
11     mentor::memory_bist::DftSpecification {
12       SummaryInfo {
13         version 1
14         current_design corea
15         DesignInstance {
16           -
17             DesignId {
18               first_insertion {
19                 Controller {
20                   corea_first_insertion_tessent_mbist_c1_controller_inst {
21                     bist_clock_period_ns 10.0
22                     bist_clock_connection clka
23                     module_name corea_first_insertion_tessent_mbist_c1_controller
24                     design_instance corea_first_insertion_tessent_mbist_c1_controller_inst
25                     bap_module_name corea_first_insertion_tessent_mbist_bap
26                     bap_design_instance corea_first_insertion_tessent_mbist_bap_inst
27                     bist_port {corea_first_insertion_tessent_mbist_bap_inst/bistEn[0]}
28                     Step {
29                       0 {
30                         StepInfo {
31                           power_mw 0.83
32                           run_time_ns 15840.0
33                           test_cycles 1584
34                           comparator_location per_interface
35                         }
36                         MemoryInstance {
37                           ram1 {
38                             power mw 0.83
39                             interface_id m1
40                             template /Core(SYNC_1R1W_16x8)/Memory
41                             type sram
42                             object_id instance:0
43                             MemoryInterfaceInfo {
44                               design_instance ram1_interface_inst
45                               module_name corea_first_insertion_tessent_mbist_c1_interface_m1
46                             }
47                             logical_ports 1R1W
48                             test_ports 1
49                           }
50                         }
51                       }
52                     }
53                     power_mw 0.83
54                     run_time_ns 15840.0
55                     test_cycles 1584
56                     flop_count 115
57                     soft_instruction_count 0
58                   }
59                   corea_first_insertion_tessent_mbist_c2_controller_inst {
60                     bist_clock_period_ns 13.2
61                     bist_clock_connection clkb
62                     module_name corea_first_insertion_tessent_mbist_c2_controller
63                     design_instance corea_first_insertion_tessent_mbist_c2_controller_inst
64                     bap_module_name corea_first_insertion_tessent_mbist_bap
65                     bap_design_instance corea_first_insertion_tessent_mbist_bap_inst
66                     bist_port {corea_first_insertion_tessent_mbist_bap_inst/bistEn[1]}
67                     Step {
68                       0 {
69                         StepInfo {
70                           power_mw 0.63
71                           run_time_ns 20908.8
72                           test_cycles 1584
73                         }
74                       }
75                     }
76                   }
77                 }
78               }
79             }
80           }
81         }
82       }
83     }
84   }
85 }
```

For Controller C1 in step 0 it is controlling RAM1

For Controller C2 in step 0 it is controlling RAM2

NOTE :

Suppose if a particular controller is controlling so memories, then the tool will automatically divide it into steps

i.e in step 0 → 25 mem

in step 1 → 25 mem

In our lab, we are having 2 controllers
i.e controller c1 → ram1 (1mem)
controller c2 → ram2 (1mem)

ram1 is controlled in step 0 of c1

ram2 is controlled in step 0 of c2.

6. Modified Rtl files

```
module corea (clk_a, clk_b, clk_c, scan_en, test_clock, rst, in_a, in_b, out_a, out_b,
    ijttag_tck, ijttag_reset, ijttag_ce, ijttag_se, ijttag_ue, ijttag_sel,
    ijttag_si, ijttag_so);
input clk_a;
input clk_b;
input clk_c;
input rst;
input scan_en, test_clock;

input [31:0] in_a, in_b;
output [31:0] out_a, out_b;
    input ijttag_tck, ijttag_reset, ijttag_ce, ijttag_se, ijttag_ue, ijttag_sel,
        ijttag_si;
    wire ijttag_tck, ijttag_reset, ijttag_ce, ijttag_se, ijttag_ue, ijttag_sel,
        ijttag_si;
    output ijttag_so;
    wire ijttag_so;

reg [31:0] ffa1, ffa2, ffa3, ffa4;
reg [31:0] ffb1, ffb2, ffb3, ffb4;
reg [31:0] ffcl;
reg         rsta, rstb, rstc;
wire      ena, enb;
wire [7:0] ram1_q, ram2_q;
    wire [1:0] toBist;
    wire [2:0] BIST_COL_ADD, BIST_COL_ADD_ts1;
    wire [1:0] BIST_WRITE_DATA, BIST_WRITE_DATA_ts1, BIST_EXPECT_DATA,
        BIST_EXPECT_DATA_ts1;
    wire [7:0] GWE, GWE_ts1;
    wire [3:0] ram1_interface_inst_AR, ram2_interface_inst_AR,
        ram1_interface_inst_AW, ram2_interface_inst_AW;
    wire corea first insertion tesson sib mbist inst so,
```

This is the design after all the IJTAG and MBIST inserted, so this is the final netlist after mbist insertion run.

Module instantiation of a SIB:

```
169 corea_first_insertion_tessent_sib_1 corea_first_insertion_tessent_sib_sti_inst(
170     .ijtag_reset(ijtag_reset), .ijtag_sel(ijtag_sel), .ijtag_si(ijtag_si), .ijtag_ce(ijtag_ce),
171     .ijtag_se(ijtag_se), .ijtag_ue(ijtag_ue), .ijtag_tck(ijtag_tck), .ijtag_so(corea_first_insertion_tessent_sib_sti_in-
st_so),
172     .ijtag_from_so(corea_first_insertion_tessent_sib_mbist_inst_so), .ltest_si(1'b0),
173     .ltest_scan_en(scan_en), .ltest_en(ltest_en), .ltest_clk(test_clock), .ltest_mem_bypass_en(1'b1),
174     .ltest_mcp_bounding_en(1'b0), .ltest_occ_en(1'b0), .ltest_async_set_reset_static_disable(1'b0),
175     .ltest_static_clock_control_mode(1'b0), .ltest_clock_sequence({1'b0,
176     1'b0}), .ltest_so(), .to_ijtag_reset(to_ijtag_reset), .ltest_to_en(ltest_to_en),
177     .to_ijtag_si(corea_first_insertion_tessent_sib_sti_inst_so_ts1), .to_ijtag_ce(to_ijtag_ce),
178     .to_ijtag_se(to_ijtag_se), .to_ijtag_ue(to_ijtag_ue), .to_ijtag_tck(to_ijtag_tck),
179     .ltest_to_mem_bypass_en(ltest_to_mem_bypass_en), .ltest_to_mcp_bounding_en(ltest_to_mcp_bounding_en),
180     .ltest_to_scan_en(ltest_to_scan_en), .ijtag_to_sel(corea_first_insertion_tessent_sib_sti_inst_to_select)
181 );
182
183 corea_first_insertion_tessent_sib_2 corea_first_insertion_tessent_sib_sri_inst(
184     .ijtag_reset(ijtag_reset), .ijtag_sel(ijtag_sel), .ijtag_si(corea_first_insertion_tessent_sib_sti_inst_so),
185     .ijtag_ce(ijtag_ce), .ijtag_se(ijtag_se), .ijtag_ue(ijtag_ue), .ijtag_tck(ijtag_tck),
186     .ijtag_so(ijtag_so), .ijtag_from_so(corea_first_insertion_tessent_tdr_sri_ctrl_inst_so),
187     .ijtag_to_sel(corea_first_insertion_tessent_sib_sri_inst_to_select)
188 );
```

How the SIB has to operate here that is not available here? So where it will be available ?

- It will be available in instruments directory individually for all the SIBs, TDRs, controllers, BAP, verilog and ICL file.

So the tool will understand the functionality of the SIBs, TDRs, controller BAP, verilog and ICL file from taking information form the instruments directory.

INSTRUMENTS:-

1. For MBIST

```
/home/vinayakp/aug23/level3/Lab0/tsdb_outdir>>ll
total 0
drwxr-xr-x. 4 vinayakp vinayakp 137 Dec 23 12:20 dft_inserted_designs
drwxr-xr-x. 5 vinayakp vinayakp 144 Dec 23 12:19 instruments
drwxr-xr-x. 3 vinayakp vinayakp 46 Dec 22 12:22 logic_test_cores
drwxr-xr-x. 3 vinayakp vinayakp 103 Dec 22 12:22 patterns
/home/vinayakp/aug23/level3/Lab0/tsdb_outdir>>cd instruments/
/home/vinayakp/aug23/level3/Lab0/tsdb_outdir/instruments>>ls
corea_first_insertion_cells.instrument corea_first_insertion_mbist.instrument
corea_first_insertion_ijtag.instrument
/home/vinayakp/aug23/level3/Lab0/tsdb_outdir/instruments>>cd corea_first_insertion_mbist.instrument
/home/vinayakp/aug23/level3/Lab0/tsdb_outdir/instruments/corea_first_insertion_mbist.instrument>>ls
corea_first_insertion_mbist.sdc_dictionary
corea_first_insertion_mbist.synthesis_dictionary
corea_first_insertion_tessent_mbist_bap.icl
corea_first_insertion_tessent_mbist_bap.tcd
corea_first_insertion_tessent_mbist_bap.v
corea_first_insertion_tessent_mbist_c1_controller_assembly.design_source_dictionary
corea_first_insertion_tessent_mbist_c1_controller_assembly.icl
corea_first_insertion_tessent_mbist_c1_controller_assembly.sdc
corea_first_insertion_tessent_mbist_c1_controller_assembly.v
corea_first_insertion_tessent_mbist_c1_controller.icl
corea_first_insertion_tessent_mbist_c1_controller.pdl
corea_first_insertion_tessent_mbist_c1_controller.tcd
corea_first_insertion_tessent_mbist_c1_controller.tessent_connection_info
corea_first_insertion_tessent_mbist_c1_controller.v
corea_first_insertion_tessent_mbist_c1.generation_log
corea_first_insertion_tessent_mbist_c1_interface_m1.icl
corea_first_insertion_tessent_mbist_c1_interface_m1.v
corea_first_insertion_tessent_mbist_c2_controller_assembly.design_source_dictionary
corea_first_insertion_tessent_mbist_c2_controller_assembly.icl
corea_first_insertion_tessent_mbist_c2_controller_assembly.sdc
corea_first_insertion_tessent_mbist_c2_controller_assembly.v
corea_first_insertion_tessent_mbist_c2_controller.icl
corea_first_insertion_tessent_mbist_c2_controller.pdl
corea_first_insertion_tessent_mbist_c2_controller.tcd
corea_first_insertion_tessent_mbist_c2_controller.tessent_connection_info
corea_first_insertion_tessent_mbist_c2_controller.v
corea_first_insertion_tessent_mbist_c2.generation_log
corea_first_insertion_tessent_mbist_c2_interface_m1.icl
corea_first_insertion_tessent_mbist_c2_interface_m1.v
SYNC_1RIW_16x8.icl
SYNC_1RIW_16x8.scan
SYNC_1RIW_16x8.syn
```

2. For ICL

```
/home/vinayakp/aug23/level3/Lab0/tsdb_outdir/instruments>>ll
total 8
drwxrwxr-x. 2 vinayakp vinayakp 128 Dec 23 12:19 corea_first_insertion_cells.instrument
drwxrwxr-x. 2 vinayakp vinayakp 4096 Dec 23 12:19 corea_first_insertion_ijtag.instrument
drwxrwxr-x. 2 vinayakp vinayakp 4096 Dec 23 12:20 corea_first_insertion_mbist.instrument
/home/vinayakp/aug23/level3/Lab0/tsdb_outdir/instruments>>cd corea_first_insertion_ijtag.instrument
/home/vinayakp/aug23/level3/Lab0/tsdb_outdir/instruments/corea_first_insertion_ijtag.instrument>>ll
total 60
-rw-rw-r--. 1 vinayakp vinayakp 2049 Dec 23 12:19 corea_first_insertion_ijtag.synthesis_dictionary
-rw-rw-r--. 1 vinayakp vinayakp 2798 Dec 23 12:19 corea_first_insertion_tessent_sib_1.ctl
-rwrxrwxr-x. 1 vinayakp vinayakp 4014 Dec 23 12:19 corea_first_insertion_tessent_sib_1.icl
-rwrxrwxr-x. 1 vinayakp vinayakp 1263 Dec 23 12:19 corea_first_insertion_tessent_sib_1.pdl
-rwrxrwxr-x. 1 vinayakp vinayakp 1974 Dec 23 12:19 corea_first_insertion_tessent_sib_1.tcd
-rwrxrwxr-x. 1 vinayakp vinayakp 1402 Dec 23 12:19 corea_first_insertion_tessent_sib_1.tcd_scan
-rwrxrwxr-x. 1 vinayakp vinayakp 7377 Dec 23 12:19 corea_first_insertion_tessent_sib_1.v
-rwrxrwxr-x. 1 vinayakp vinayakp 1848 Dec 23 12:19 corea_first_insertion_tessent_sib_2.icl
-rwrxrwxr-x. 1 vinayakp vinayakp 1981 Dec 23 12:19 corea_first_insertion_tessent_sib_2.v
-rwrxrwxr-x. 1 vinayakp vinayakp 1780 Dec 23 12:19 corea_first_insertion_tessent_sib_3.icl
-rwrxrwxr-x. 1 vinayakp vinayakp 1981 Dec 23 12:19 corea_first_insertion_tessent_sib_3.v
-rwrxrwxr-x. 1 vinayakp vinayakp 1910 Dec 23 12:19 corea_first_insertion_tessent_tdr_sri_ctrl.icl
-rwrxrwxr-x. 1 vinayakp vinayakp 1629 Dec 23 12:19 corea_first_insertion_tessent_tdr_sri_ctrl.v
-rw-rw-r--. 1 vinayakp vinayakp 1859 Dec 23 12:19 ijtag.sdc_dictionary
```

PATTERNS:-

```
/home/vinayakp/aug23/level3/Lab0/tsdb_outdir>>cd patterns/
/home/vinayakp/aug23/level3/Lab0/tsdb_outdir/patterns>>ls
corea_first_insertion.patterns_signoff corea_first_insertion.patterns_spec_signoff
/home/vinayakp/aug23/level3/Lab0/tsdb_outdir/patterns>>cd corea_first_insertion.patterns_signoff
/home/vinayakp/aug23/level3/Lab0/tsdb_outdir/patterns/corea_first_insertion.patterns_signoff>>ll
total 596
-rwxr-xr-x. 1 vinayakp vinayakp 21450 Dec 23 10:44 ICLNetwork.pdl
-rwxr-xr-x. 1 vinayakp vinayakp 49035 Dec 23 10:44 ICLNetwork.v
-rwxr-xr-x. 1 vinayakp vinayakp 34119 Dec 23 10:44 ICLNetwork.v.0.vec
-rwxr-xr-x. 1 vinayakp vinayakp 25 Dec 23 10:44 ICLNetwork.v.cfg
-rwxr-xr-x. 1 vinayakp vinayakp 17 Dec 23 10:44 ICLNetwork.v.po.name
-rwxr-xr-x. 1 vinayakp vinayakp 38460 Dec 23 10:44 MemoryBist_P1.pdl
-rwxr-xr-x. 1 vinayakp vinayakp 65419 Dec 23 10:44 MemoryBist_P1.v
-rwxr-xr-x. 1 vinayakp vinayakp 68155 Dec 23 10:44 MemoryBist_P1.v.0.vec
-rwxr-xr-x. 1 vinayakp vinayakp 28 Dec 23 10:44 MemoryBist_P1.v.cfg
-rwxr-xr-x. 1 vinayakp vinayakp 17 Dec 23 10:44 MemoryBist_P1.v.po.name
-rwxr-xr-x. 1 vinayakp vinayakp 84079 Dec 23 10:44 MemoryBist_parallelRetentionTest_P1.pdl
-rwxr-xr-x. 1 vinayakp vinayakp 62514 Dec 23 10:44 MemoryBist_parallelRetentionTest_P1.v
-rwxr-xr-x. 1 vinayakp vinayakp 136691 Dec 23 10:44 MemoryBist_parallelRetentionTest_P1.v.0.vec
-rwxr-xr-x. 1 vinayakp vinayakp 51 Dec 23 10:44 MemoryBist_parallelRetentionTest_P1.v.cfg
-rwxr-xr-x. 1 vinayakp vinayakp 17 Dec 23 10:44 MemoryBist_parallelRetentionTest_P1.v.po.name
-rwxr-xr-x. 1 vinayakp vinayakp 4535 Dec 23 10:44 simulation.data_dictionary
/home/vinayakp/aug23/level3/Lab0/tsdb_outdir/patterns/corea_first_insertion.patterns_signoff>>
```

- It will be having TB file, PDL file, vector file, memory MBIST simulation, parallel retention test, ICL network.

```
/home/vinayakp/aug23/level3/Lab0>>ll
total 4
drwxr-xr-x. 3 vinayakp vinayakp 16 Dec 22 12:22 atpg
drwxr-xr-x. 2 vinayakp vinayakp 21 Dec 22 12:22 design
drwxr-xr-x. 3 vinayakp vinayakp 4096 Dec 23 13:57 mbist_insertion
drwxr-xr-x. 2 vinayakp vinayakp 52 Dec 22 12:22 scan_insertion
drwxr-xr-x. 3 vinayakp vinayakp 93 Dec 22 12:22 synthesis
drwxr-xr-x. 6 vinayakp vinayakp 93 Dec 22 12:22 tsdb_outdir
/home/vinayakp/aug23/level3/Lab0>>cd mbist_insertion/
/home/vinayakp/aug23/level3/Lab0/mbist_insertion>>ls
\ corea_mbist.tcl schematic_ijtag_network.tcl simulation_outdir
corea_dc_shell_import_script schematic_ijatg_network.tcl schematic_IJTAG_Netwrok.tcl
/home/vinayakp/aug23/level3/Lab0/mbist_insertion>>cd simulation_outdir/
/home/vinayakp/aug23/level3/Lab0/mbist_insertion/simulation_outdir>>ls
corea_first_insertion.simulation_signoff
/home/vinayakp/aug23/level3/Lab0/mbist_insertion/simulation_outdir>>cd corea_first_insertion.simulation_signoff/
/home/vinayakp/aug23/level3/Lab0/mbist_insertion/simulation_outdir/corea_first_insertion.simulation_signoff>>ls
ICLNetwork.simulation MemoryBist_parallelRetentionTest_P1.simulation
MemoryBist_P1.simulation patterns_directory
/home/vinayakp/aug23/level3/Lab0/mbist_insertion/simulation_outdir/corea_first_insertion.simulation_signoff>>cd
MemoryBist_P1.simulation
/home/vinayakp/aug23/level3/Lab0/mbist_insertion/simulation_outdir/corea_first_insertion.simulation_signoff/MemoryBist_P1.simulation>>ls
dut_work patterns.configuration questa.arguments_1 questa.setup_script questa.simulation_script
modelsim.ini patterns_directory questa.arguments_2 questa.simulation_log transcript
```

1. Questa simulation script for MemoryBist_P1.simulation

```
1#!/bin/sh
2unset noclobber
3xitval=0
4
5if [ -f ./questa.setup_script ] ; then
6  . ./questa.setup_script
7fi
8
9echo "Number of expected miscompares = 0"
10set -v
11
12
13vlib dut_work
14vmap dut_work dut_work
15
16
17# Entry 1
18vlog -work dut_work -L dut_work -mixedansiports +librescan -ysearchlib -mfcu \
19      "../../../../tsdb_outdir/dft_inserted_designs/corea_first_insertion.dft_inserted_design/modified_rtl_files/corea.v"
20      -f questa.arguments_1
21if [ $? != 0 ] ; then
22  xitval=-1; echo "Failure on entry 1"; fi
22
23# Entry 2
24vlog -work dut_work -L dut_work -mixedansiports +librescan -ysearchlib -mfcu \
25      "../../../../tsdb_outdir/instruments/corea_first_insertion_cells.instrument/corea_first_insertion_tessent_posedge_synchronizer_reset.v" \
26      -f questa.arguments_1
27if [ $? != 0 ] ; then
28  xitval=-1; echo "Failure on entry 2"; fi
28
29# Entry 3
30vlog -work dut_work -L dut_work -mixedansiports +librescan -ysearchlib -mfcu \
@      "../../../../tsdb_outdir/instruments/corea_first_insertion_ijtag.instrument/corea_first_insertion_tessent_sib_1.v"
31      "../../../../tsdb_outdir/instruments/corea_first_insertion_ijtag.instrument/corea_first_insertion_tessent_sib_2.v"
32      "../../../../tsdb_outdir/instruments/corea_first_insertion_ijtag.instrument/corea_first_insertion_tessent_sib_3.v"
33      "../../../../tsdb_outdir/instruments/corea_first_insertion_ijtag.instrument/corea_first_insertion_tessent_tdr_sri_ctrl.v" \
34      -f questa.arguments_1
35if [ $? != 0 ] ; then
36  xitval=-1; echo "Failure on entry 3"; fi
37
38# Entry 4
39vlog -work dut_work -L dut_work -mixedansiports +librescan -ysearchlib -mfcu \
40      "../../../../tsdb_outdir/instruments/corea_first_insertion_mbist.instrument/corea_first_insertion_tessent_mbist_bap.v" \
41      "../../../../tsdb_outdir/instruments/corea_first_insertion_mbist.instrument/corea_first_insertion_tessent_mbist_c1_controller.v" \
42      "../../../../tsdb_outdir/instruments/corea_first_insertion_mbist.instrument/corea_first_insertion_tessent_mbist_c1_interface_m1.v" \
43      "../../../../tsdb_outdir/instruments/corea_first_insertion_mbist.instrument/corea_first_insertion_tessent_mbist_c2_controller.v" \
44      "../../../../tsdb_outdir/instruments/corea_first_insertion_mbist.instrument/corea_first_insertion_tessent_mbist_c2_interface_m1.v" \
45      -f questa.arguments_1
46if [ $? != 0 ] ; then
47  xitval=-1; echo "Failure on entry 4"; fi
47
48# Entry 5
49vlog -work dut_work -L dut_work -mixedansiports +librescan -ysearchlib -mfcu \
50      "./patterns_directory/MemoryBist_P1.v" \
51      -f questa.arguments_2
52if [ $? != 0 ] ; then
53  xitval=-1; echo "Failure on entry 5"; fi
53
54# Entry 6
```

```

54 # Entry 6
55 vlog -work dut_work -L dut_work -mixedansiports +librescan -ysearchlib -mfcu \
56     "./patterns.configuration"
57 if [ $? != 0 ] ; then xitval=-1; echo "Failure on entry 6"; fi
58
59 if [ $xitval -ne 0 ]; then
60   echo "Compilation failed"
61   exit $xitval
62 fi
63
64 vsim -c -lib "dut_work" -L dut_work -do 'run -all; exit' +nowarnTFMPC +NEWPATH=./patterns_directory \
65     MemoryBist_P1_configuration
66 if [ $? != 0 ] ; then xitval=-1; fi
67
68 if [ $xitval -ne 0 ]; then
69   echo "Simulation failed"
70 fi
71
72 exit $xitval

```

Here the tool is doing the TB file, IP file while giving the command only it is keeping it
Instead of keeping it in a file verilog file.list

It is directly keeping while giving a vlog command itself

So the script will automatically written by tool, tool is automatically writing this

- Instead of keeping verilog log file.list it will directly read during the vlog command.
- And vlog sim command it will directly reading the TB file.

So in corea.v only module instantiation will be there from line 19

And module def will be there in Entry 3 and Entry 4

In Entry 5, tool is reading the TB file(MemoryBist_P1.v) inside the patterns directory

Line 64: run -all, it will be done with simulations

So go to the questa.simulation_log file to check whether it is passing or failing

```

# 8600ns: Enabling reduced address simulation
# 8600ns: Enabling reduced address simulation
# 26000ns: Checking GO is FAIL before execution
# 26000ns: Checking DONE is FAIL before execution
# 26000ns: Starting MemoryBist controller execution : corea_first_insertion_tessent_mbist_c1_controller_inst
# 26000ns: Checking GO is FAIL before execution
# 26000ns: Checking DONE is FAIL before execution
# 26000ns: Starting MemoryBist controller execution : corea_first_insertion_tessent_mbist_c2_controller_inst
# 50300ns: Checking GO is PASS after execution completion
# 50300ns: Checking DONE is PASS after execution completion
# 50300ns: Checking GO is PASS after execution completion
# 50300ns: Checking DONE is PASS after execution completion
# 55900ns: Checking GO_ID bits are PASS
# 55900ns: Checking GO_ID bits are PASS
#
# Simulation finished at time 71901
# Number of miscomparisons      =          0
# Number of 0/1 compares         =        181
# Number of Z compares           =          0

```

Go to patterns directory

b. From ICLnetwork.Simulation

```
48 # Entry 5
49 vlog -work dut_work -L dut_work -mixedansiports +librescan -ysearchlib -mfcu \
50     "./patterns_directory/ICLNetwork.v" \
51     -f questa.arguments_2
52 if [ $? != 0 ] ; then xitval=-1; echo "Failure on entry 5"; fi
53
54 # Entry 6
55 vlog -work dut_work -L dut_work -mixedansiports +librescan -ysearchlib -mfcu \
56     "./patterns.configuration"
57 if [ $? != 0 ] ; then xitval=-1; echo "Failure on entry 6"; fi
58
59 if [ $xitval -ne 0 ]; then
60     echo "Compilation failed"
61     exit $xitval
62 fi
63
64 vsim -c -lib "dut_work" -L dut_work -do 'run -all; exit' +nowarnTFMPC +NEWPATH=./patterns_directory \
65     ICLNetwork_configuration
66 if [ $? != 0 ] ; then xitval=-1; fi
67
68 if [ $xitval -ne 0 ]; then
69     echo "Simulation failed"
70 fi
71
72 exit $xitval
```

From MBIST Insertion, it will read the TB of MBIST TB but in ICLNetwork tool will be reading the ICLNetwork testbench i.e. (ICLNetwork.v) and other than that everything will remain unchanged.

```
"# Simulation finished at time 13401
# Number of miscompares      =
# Number of 0/1 compares      =
# Number of Z compares        =
#
# No error between simulated and expected patterns
#
# ** Note: $finish : ./patterns_directory/ICLNetwork.v(1262)
#   Time: 13402 ns  Iteration: 0  Instance: /TB
# End time: 10:44:34 on Dec 23,2023, Elapsed time: 0:00:01
# Errors: 0, Warnings: 0
if [ $? != 0 ] ; then xitval=-1; fi

if [ $xitval -ne 0 ]; then
    echo "Simulation failed"
fi

exit $xitval
exit0
```

c. From MemoryBIST_ParallelRetention Test_P1

```
"# Simulation finished at time 111101
# Number of miscompares      =
# Number of 0/1 compares      =
# Number of Z compares        =
#
# No error between simulated and expected patterns
#
# ** Note: $finish : ./patterns_directory/MemoryBist_ParallelRetentionTest_P1.v(1580)
#   Time: 111102 ns  Iteration: 0  Instance: /TB
# End time: 10:44:38 on Dec 23,2023, Elapsed time: 0:00:00
# Errors: 0, Warnings: 0
if [ $? != 0 ] ; then xitval=-1; fi

if [ $xitval -ne 0 ]; then
    echo "Simulation failed"
fi

exit $xitval
exit0
```

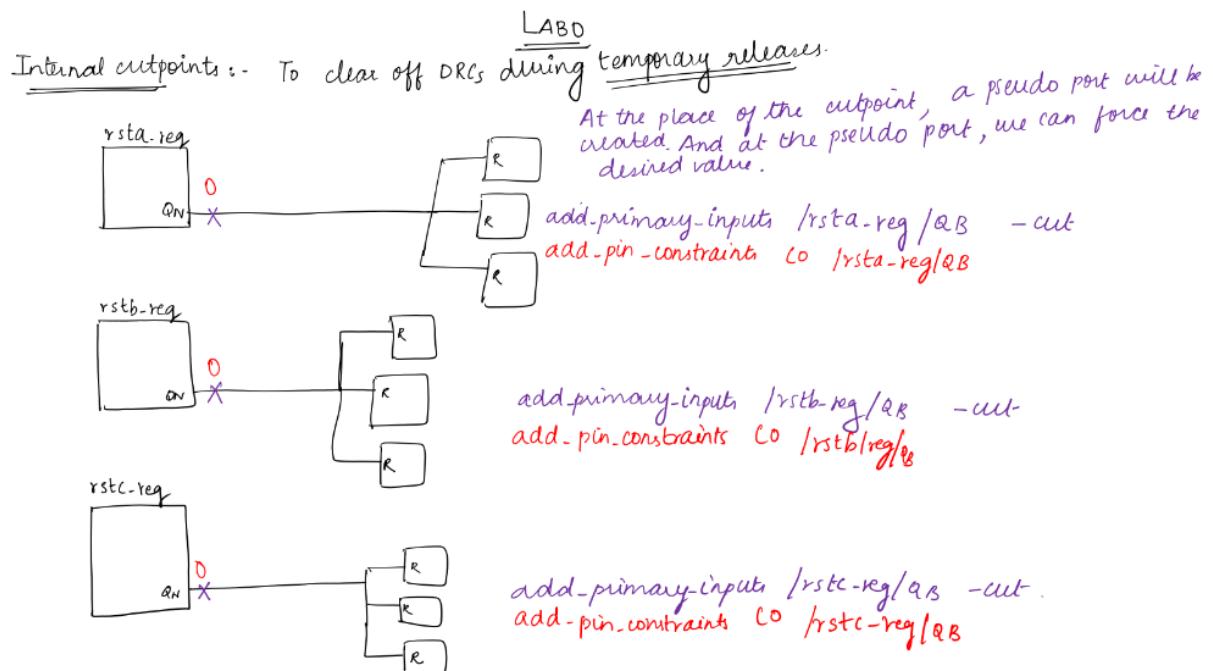
Step 2: Scan Insertion

```

1 set_context dft -scan -design_id corea_scan -hierarchical
2
3 set_tsdb_output_directory ..//tsdb_outdir
4
5 read_cell_library ../../library/adk.tcelllib
6
7 read_verilog ../../library/mems/SYNC_1R1W_16x8.v -interface_only
8
9 read_verilog ./synthesis/outputs/corea_top_gate.v
10
11 read_design corea -design_id first_insertion -icl_only -verbose
12
13 set_current_design corea
14
15 set_design_level physical_block
16
17 delete_clocks -all
18
19 ## added all below clocks as -pulse_in_capture since OCC is not implemented in this session and all functional clocks are
   considered as scan clocks
20 add_clocks 0 clka -pulse_in_capture
21 add_clocks 0 clkb -pulse_in_capture
22 add_clocks 0 clkc -pulse_in_capture
23 add_clocks 0 test_clock -pulse_in_capture
24 add_clocks 1 rst -pulse_in_capture
25 |
26 add_primary_inputs /rsta_reg/QB -cut
27 add_primary_inputs /rstb_reg/QB -cut
28 add_primary_inputs /rstc_reg/QB -cut
29
30 add_pin_constraints C0 /rsta_reg/QB
31 add_pin_constraints C0 /rstb_reg/QB
32 add_pin_constraints C0 /rstc_reg/QB
33
34 chec_design_rules
35
36 add_scan_mode no_wrapper_mode -chain_length 50
37
38 analyze_scan_chains
39
40 insert_test_logic -write_in_tsdb on
--
```

Line 20 to 24:- We have not inserted OCC that's why we to declare as pulse in capture.

Line 26 to 32:- add_pin_constraints - It will actually add internal cut points.



- It is actually used to clear off of DRC's during the temporary releases. Finally when we deliver the pattern to the tester, then internal cut points should not be there, because what will happen is u have any internal cut points then pattern will fail in the tester, because the tester can apply the value only on EDT channel it cannot force a value on a internal ports.
- But ATPG tool will write a pattern by considering the internal cut points, so that is why the pattern will fail on the tester.
- So only for temporary releases we can clear of the DRC using internal cut points
- So for final release we have to remove the internal cut points.

So we are forcing a off state values at the flops which is a active high reset. (0 - off state that is inactive is forced here), hence we are propagating a offstate value.

Wherever the cut point is created, a pseudo port will be created and we will able to force a desired value on pseudo port.

Line 36: we are inserting any wrapper

Line 38: It will distribute various flops into different scan chains.

Line 40: It will replace the normal flops with scan flops and it will do scan chain stitching, and - write_in_tsdb have been generated which will be written into the tsdb output directory.

```
/home/vinayakp/aug23/level3/Lab0/scan_insertion>>tessent -shell -dofile corea_scan.tcl
// Warning: Tessent user documentation not found
// Tessent Shell 2021.1   Fri Feb 26 20:45:56 GMT 2021
// Copyright 2011-2021 Mentor Graphics Corporation
//
// All Rights Reserved.
//
// THIS WORK CONTAINS TRADE SECRET AND PROPRIETARY INFORMATION WHICH
// IS THE PROPERTY OF MENTOR GRAPHICS CORPORATION OR ITS LICENSORS AND IS
// SUBJECT TO LICENSE TERMS.
//
// Mentor Graphics software executing under x86-64 Linux on Sun Jan 28 17:48:12 IST 2024.
// 64 bit version
// Host: vlsiguru (64168 MB RAM, 32191 MB Swap)
//
// command: set_context dft -scan -design_id corea_scan -hierarchical
// command: set_tsdb_output_directory ../../tsdb_outdir
// command: read_cell_library ../../library/adk.tcelllib
// Reading DFT Library file ../../library/adk.tcelllib
// Finished reading file ../../library/adk.tcelllib
// command: read_verilog ../../library/mems/SYNC_1R1W_16x8.v -interface_only
// command: read_verilog ../../synthesis/outputs/corea_top_gate.v
// command: read_design corea -design_id first_insertion -icl_only -verbose
// sub-command: read_icl ../../tsdb_outdir/dft_inserted_designs/corea_first_insertion.dft_inserted_design/corea.icl -skip_child_blocks -no_notes
// sub-command: source ../../tsdb_outdir/dft_inserted_designs/corea_first_insertion.dft_inserted_design/corea.pdl
// sub-command: read_core_descriptions ../../tsdb_outdir/dft_inserted_designs/corea_first_insertion.dft_inserted_design/corea.tcd
// command: set_current_design corea
// Warning: 9 cases: Undriven net in netlist module
// Warning: 57 cases: Net in netlist not connected
// Note: Issue set_current_design with the -show_elaboration_warnings option to see more details about previous
// warnings
// -----
..
```

```

// -----
// Begin ICL elaboration and checking.
// -----
// ICL elaboration completed, CPU time=0.13 sec.
// -----
// command: set_design_level physical_block
// command: delete_clocks -all
// command: ## added all below clocks as -pulse_in_capture since OCC is not implemented in this session and all
// functional clocks are considered as scan clocks
// command: add_clocks 0 clka -pulse_in_capture
// command: add_clocks 0 clkcb -pulse_in_capture
// command: add_clocks 0 clkcc -pulse_in_capture
// command: add_clocks 0 test_clock -pulse_in_capture
// command: add_clocks 1 rst -pulse_in_capture
// command: add_primary_inputs /rsta_reg/QB -cut
// Warning: Primary input 'rsta_reg/QB_pport' is added at pin '/rsta_reg/QB'
// command: add_primary_inputs /rstb_reg/QB -cut
// Warning: Primary input 'rstb_reg/QB_pport' is added at pin '/rstb_reg/QB'
// command: add_primary_inputs /rstc_reg/QB -cut
// Warning: Primary input 'rstc_reg/QB_pport' is added at pin '/rstc_reg/QB'
// command: add_pin_constraints C0 /rsta_reg/QB
// command: add_pin_constraints C0 /rstb_reg/QB
// command: add_pin_constraints C0 /rstc_reg/QB
// command: check_design_rules
// Warning: Rule FN1 violation occurs 82 times
// Warning: Rule FN4 violation occurs 672 times
// Flattening process completed, cell instances=5973, gates=9445, PIs=77+4(pseudo ports), P0s=65, CPU time=0.05
sec.
// -----
// Begin circuit learning analyses.
// -----
// Learning completed, CPU time=0.04 sec.
// -----
// Begin scan chain identification process, memory elements = 672,
// sequential library cells = 672.
// -----
// Begin simulation of test_setup procedure with 18 cycles.
// Simulation of test_setup procedure completed, CPU time=0.0 sec.
// Begin simulation of auto-generated load_unload procedure.
// Simulation of load_unload procedure completed, CPU time=0.0 sec.
// Scan segment = /corea_first_insertion_tessent_sib_sti_inst/ltest_so successfully traced with scan_cells = 7.
// 7 scan cells have been identified in 1 scan segment.
// Warning: 1 edge-triggered clock ports set to stable high. (D7)
// Warning: Model 'nlatch' has no muxscan scan equivalent and is treated as nonscan model
// -----
// 20 sequential library cells are treated as non-scan.
// -----
// 8 sequential library cells missing mux-scan equivalent.
// 5 sequential library cells below hard module.
// 7 sequential library cells defined non-scan.
// -----
// Begin scannability rules checking for 642 sequential library cells
// and 1 scan segment. The scan segment contains 10 additional cells.
// -----
// Note: There were 3 S7 violations (Potentially scannable cell that is not in the clock path is driven by a co
nstant value).
// 642 sequential library cells and 1 scan segment identified as scannable.
// -----
// Begin transparent latch checking for 11 latches.
// -----
// Warning: 1 latches not transparent due to unobservable. (D6)
// Number transparent latches = 10.
// -----
// Begin scan clock rules checking.

```

```

// 7 scan clock/set/reset lines have been identified.
// All scan clocks successfully passed off-state check.
// 317 sequential cells passed clock stability checking.
// There were 23 clock rule C3 fails (clock may capture data affected by its captured data).
// Note: Trailing edge triggered device can capture data affected by leading edge.
// -----
// 22 non-scan memory elements are identified.
// -----
// 8 non-scan memory elements are identified as TIE-0. (D5)
// 3 non-scan memory elements are identified as TIE-1. (D5)
// 1 non-scan memory element is identified as TIE-X. (D5)
// 10 non-scan memory elements are identified as TLA. (D5)
// -----
// -----
// Begin shift register identification for 642 sequential library cells.
// -----
// Number of shift register flops recorded for scan insertion: 36 (5.36%)
// Number of shift registers recorded for scan insertion: 17
// Longest shift register has 3 flops.
// Shortest shift register has 2 flops.
// Potential number of nonscan flops to be converted to scan cells: 17
// Potential number of scan cells to be converted to nonscan flops: 0
// Number of targeted sequential library cells = 642
// command: add_scan_mode no_wrapper_mode -chain_length 50
// command: analyze_scan_chains
// Chain allocation of 'no_wrapper_mode' mode completed:
Distribution - populating 'no_wrapper_mode' chains: 100.0% completed (estimated time remaining 0 secs)//
13 distributed chains of sizes ranging from 49 to 50
// command: insert_test_logic -write_in_tsdb on

Test Logic Insertion Summary:
=====

Structural Data:
-----
      Added top-level port count:          2
      Added instance count:            32

Logical Data:
-----
      Added retiming logic count:        17
      Added scan chain count (no_wrapper_mode): 13

// Warning: Flattened model deleted.
// 
// Writing out netlist and related files in ../tsdb_outdir/dft_inserted_designs/corea_corea_scan.dft_inserted_design

```

Step 3: ATPG

```
1 set_context patterns -scan
2
3 set_tsdb_output_directory ../../tsdb_outdir
4
5 read_cell_library ../../library/adk.tcelllib
6
7 read_verilog ../../library/mems/SYNC_1R1W_16x8.v -interface_only
8
9 read_design corea -design_id corea_scan
10
11 set_current_design corea
12
13 set_current_mode SA -type internal
14
15 import_scan_mode no_wrapper_mode -fast_capture_mode off
16
17 add_clocks 1 rst
18
19 add_primary_inputs /rsta_reg/QB -cut
20 add_primary_inputs /rstb_reg/QB -cut
21 add_primary_inputs /rstc_reg/QB -cut
22
23 add_pin_constraints C0 /rsta_reg/QB
24 add_pin_constraints C0 /rstb_reg/QB
25 add_pin_constraints C0 /rstc_reg/QB
26 |
27 add_black_boxes -mod SYNC_1R1W_16x8
28
29 check_design_rules
30
31 set_fault_type stuck
32
33 create_patterns
34
35 write_tsdb_data -replace
36
37 system mkdir -p -v simulations
38
39 write_patterns /hdd2/home/vidishar/aug23/level3/Lab0/atpg/sa/simulations/corea_int_mode_parallel.v -verilog -parallel -re
   place -parameter_list {SIM_TOP_NAME parallel_TB SIM_KEEP_PATH 1}
40
41
```

(X) Internal cut-points is only used for temporary releases.

During the final release (i.e. when the patterns are delivered to the tester to test the chips after manufacturing), we have to make sure that we don't have any internal cut-points.

Otherwise the patterns will fail on the tester because tester can apply value only through EBT channels. It can't force a value on an internal pseudo port. Please see *

When we have used internal cutpoints, our patterns will fail during simulation as simulation tool will not understand about the cutpoint. Tool also can apply value (pattern) only on ebt channel. It can't force a value on the internal pseudo port.

So our simulation will fail if we have internal cutpoints.

For temporary releases, we can false pass the simulation by forcing the required value at the cutpoint (pseudo port). And Simulation tool also doesn't understand about the pseudo port. So it will throw an error that 'ppos' is not found.

So we have to remove all the pseudo ports from our testbench.

* ATPG tool will write patterns by considering the internal cutpoint. But tester

can't force a value on an internal pseudo port.

Why the patterns will fail when we have the internal cut points?

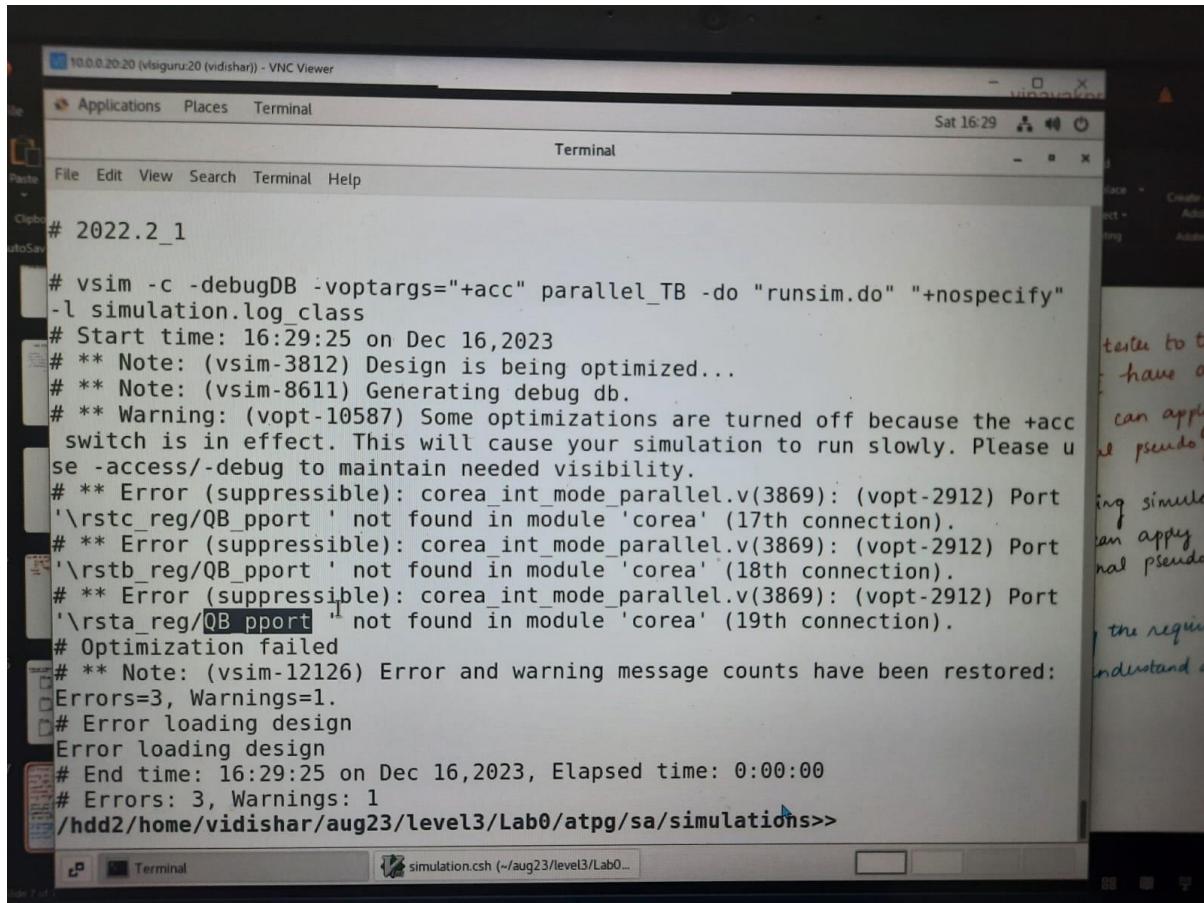
- ATPG tool it will write the pattern by considering the internal cutpoints but tester it can apply value only through EDT channel so it cannot force a value on internal pseudo port.

Statistics Report Stuck-at Faults			
Fault Classes	#faults (total)	#faults (total relevant)	
FU (full)	43476	43127	
DS (det_simulation)	34458 (79.26%)	same (79.90%)	
DI (det_implicit)	4987 (11.47%)	same (11.56%)	
UU (unused)	1128 (2.59%)	same (2.62%)	
TI (tied)	299 (0.69%)	same (0.69%)	
BL (blocked)	207 (0.48%)	same (0.48%)	
RE (redundant)	365 (0.84%)	same (0.85%)	
AU (atpg_untestable)	2032 (4.67%)	1683 (3.90%)	
<hr/>			
Fault Sub-classes			
DI (det_implicit)			
SCAN (scan_path)	2841 (6.53%)	same (6.59%)	
SEN (scan_enable)	623 (1.43%)	same (1.44%)	
CLK (clock)	1465 (3.37%)	same (3.40%)	
SR (set_reset)	4 (0.01%)	same (0.01%)	
DIN (data_input)	6 (0.01%)	same (0.01%)	
MBIST	48 (0.11%)	same (0.11%)	
AU (atpg_untestable)			
BB (black_boxes)	56 (0.13%)	same (0.13%)	
PC* (pin_constraints)	378 (0.87%)	same (0.88%)	
TC* (tied_cells)	94 (0.22%)	same (0.22%)	
SEQ (sequential_depth)	6 (0.01%)	same (0.01%)	
IJJTAG (ijtag)	349 (0.80%)	deleted	
Unclassified	1149 (2.64%)	same (2.66%)	
<hr/>			
*Use "report_statistics -detailed_analysis" for details.			
<hr/>			
Coverage			
test_coverage	95.10%	95.91%	
fault_coverage	90.73%	91.46%	
atpg_effectiveness	100.00%	100.00%	
<hr/>			
#test_patterns	286		
#basic_patterns	48		
#clock_sequential_patterns	238		
#simulated_patterns	292		
CPU_time (secs)	6.2		
<hr/>			

```
add wave -r /*;
force -freeze parallel_TB/corea_inst/rsta_reg/QB 0;
force -freeze parallel_TB/corea_inst/rstb_reg/QB 0;
force -freeze parallel_TB/corea_inst/rstc_reg/QB 0;
run -all;
```

Parallel_TB is the hierarchy and what value u are forcing that is 0.

After running the simulation it will show the error because the tool doesn't know what is pseudo port.



```

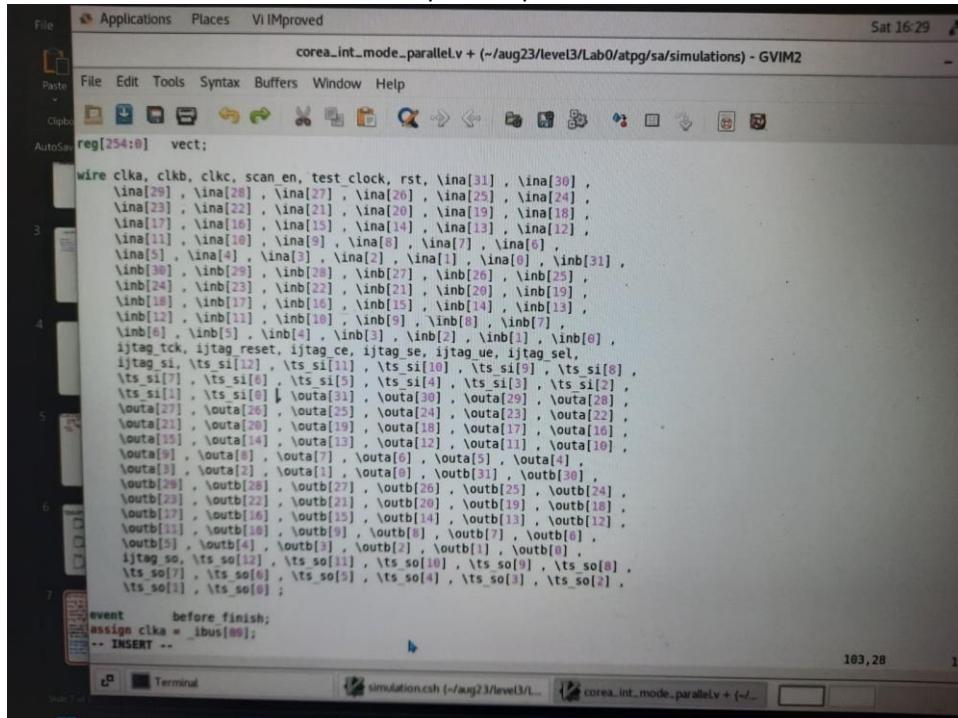
# 2022.2_1

# vsim -c -debugDB -voptargs="+acc" parallel_TB -do "runsim.do" "+nospecify"
-l simulation.log_class
# Start time: 16:29:25 on Dec 16, 2023
# ** Note: (vsim-3812) Design is being optimized...
# ** Note: (vsim-8611) Generating debug db.
# ** Warning: (vopt-10587) Some optimizations are turned off because the +acc
switch is in effect. This will cause your simulation to run slowly. Please use -access/-debug to maintain needed visibility.
# ** Error (suppressible): corea_int_mode_parallel.v(3869): (vopt-2912) Port
'\rstc_reg/QB_pport' not found in module 'corea' (17th connection).
# ** Error (suppressible): corea_int_mode_parallel.v(3869): (vopt-2912) Port
'\rstb_reg/QB_pport' not found in module 'corea' (18th connection).
# ** Error (suppressible): corea_int_mode_parallel.v(3869): (vopt-2912) Port
'\rsta_reg/QB_pport' not found in module 'corea' (19th connection).
# Optimization failed
# ** Note: (vsim-12126) Error and warning message counts have been restored:
Errors=3, Warnings=1.
# Error loading design
Error loading design
# End time: 16:29:25 on Dec 16, 2023, Elapsed time: 0:00:00
# Errors: 3, Warnings: 1
/hdd2/home/vidishar/aug23/level3/Lab0/atpg/sa/simulations>>

```

- Simulation tool will not understand what is pseudo port.

So from TB we have to remove the pseudo port.



```

reg[254:0] vect;

wire clka, clkb, clkc, scan_en, test_clock, rst, \ina[31], \ina[30],
\ina[29], \ina[28], \ina[27], \ina[26], \ina[25], \ina[24],
\ina[23], \ina[22], \ina[21], \ina[20], \ina[19], \ina[18],
\ina[17], \ina[16], \ina[15], \ina[14], \ina[13], \ina[12],
\ina[11], \ina[10], \ina[9], \ina[8], \ina[7], \ina[6],
\ina[5], \ina[4], \ina[3], \ina[2], \ina[1], \ina[0], \inb[31],
\inb[30], \inb[29], \inb[28], \inb[27], \inb[26], \inb[25],
\inb[24], \inb[23], \inb[22], \inb[21], \inb[20], \inb[19],
\inb[18], \inb[17], \inb[16], \inb[15], \inb[14], \inb[13],
\inb[12], \inb[11], \inb[10], \inb[9], \inb[8], \inb[7],
\inb[6], \inb[5], \inb[4], \inb[3], \inb[2], \inb[1], \inb[0],
ijtag_tck, ijtag_reset, ijtag_ce, ijtag_se, ijtag_ue, ijtag_sel,
ijtag_si, \ts_si[12], \ts_si[11], \ts_si[10], \ts_si[9], \ts_si[8],
\ts_si[7], \ts_si[6], \ts_si[5], \ts_si[4], \ts_si[3], \ts_si[2],
\ts_si[1], \ts_si[0], \outa[31], \outa[30], \outa[29], \outa[28],
\outa[27], \outa[26], \outa[25], \outa[24], \outa[23], \outa[22],
\outa[21], \outa[20], \outa[19], \outa[18], \outa[17], \outa[16],
\outa[15], \outa[14], \outa[13], \outa[12], \outa[11], \outa[10],
\outa[9], \outa[8], \outa[7], \outa[6], \outa[5], \outa[4],
\outa[3], \outa[2], \outa[1], \outa[0], \outb[31], \outb[30],
\outb[29], \outb[28], \outb[27], \outb[26], \outb[25], \outb[24],
\outb[23], \outb[22], \outb[21], \outb[20], \outb[19], \outb[18],
\outb[17], \outb[16], \outb[15], \outb[14], \outb[13], \outb[12],
\outb[11], \outb[10], \outb[9], \outb[8], \outb[7], \outb[6],
\outb[5], \outb[4], \outb[3], \outb[2], \outb[1], \outb[0],
ijtag_so, \ts_so[12], \ts_so[11], \ts_so[10], \ts_so[9], \ts_so[8],
\ts_so[7], \ts_so[6], \ts_so[5], \ts_so[4], \ts_so[3], \ts_so[2],
\ts_so[1], \ts_so[0];

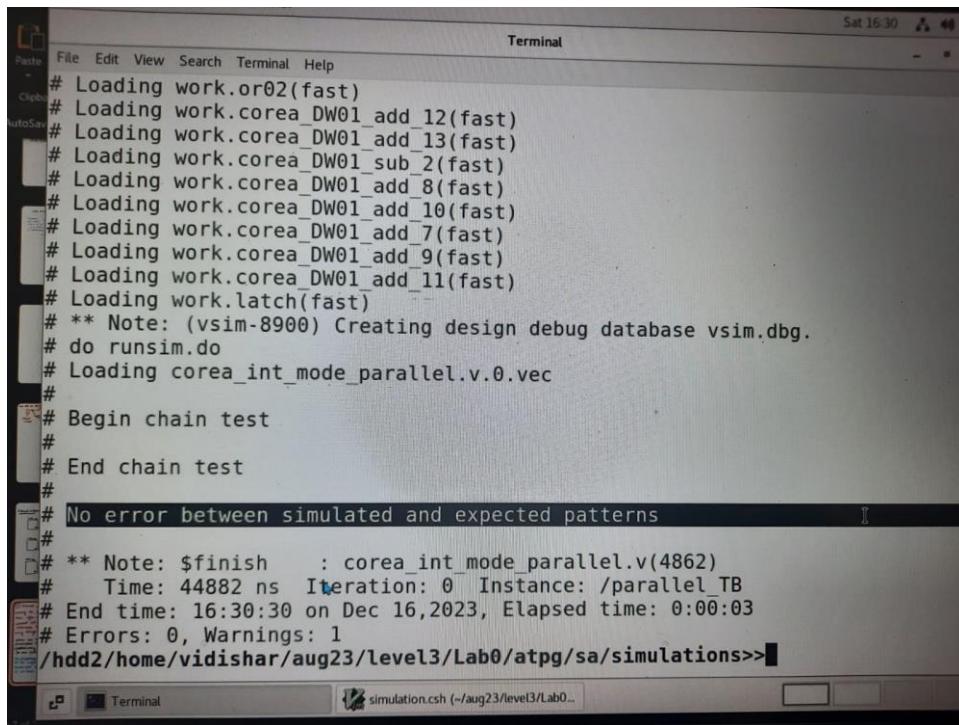
```

```

event before_finish;
assign clka = _ibus@0;
-- INSERT --

```

- After rerunning the simulation



The screenshot shows a terminal window with the following text output:

```

Sat 16:30 44
Terminal
File Edit View Search Terminal Help
# Loading work.or02(fast)
# Loading work.corea_DW01_add_12(fast)
# Loading work.corea_DW01_add_13(fast)
# Loading work.corea_DW01_sub_2(fast)
# Loading work.corea_DW01_add_8(fast)
# Loading work.corea_DW01_add_10(fast)
# Loading work.corea_DW01_add_7(fast)
# Loading work.corea_DW01_add_9(fast)
# Loading work.corea_DW01_add_11(fast)
# Loading work.latch(fast)
# ** Note: (vsim-8900) Creating design debug database vsim.dbg.
# do runsim.do
# Loading corea_int_mode_parallel.v.0.vec
#
# Begin chain test
#
# End chain test
#
# No error between simulated and expected patterns
#
# ** Note: $finish    : corea_int_mode_parallel.v(4862)
#      Time: 44882 ns Iteration: 0 Instance: /parallel_TB
# End time: 16:30:30 on Dec 16,2023, Elapsed time: 0:00:03
# Errors: 0, Warnings: 1
/hdd2/home/vidishar/aug23/level3/Lab0/atpg/sa/simulations>>

```

So, whenever we use internal cut points it can be used only to clear the DRC's during the temporary releases. But during the final releases we have to make sure.

So for Lab0, we have not inserted wrappers so we only do the intest and we are not having separate extest run.